

FIG. 1
(Prior Art)

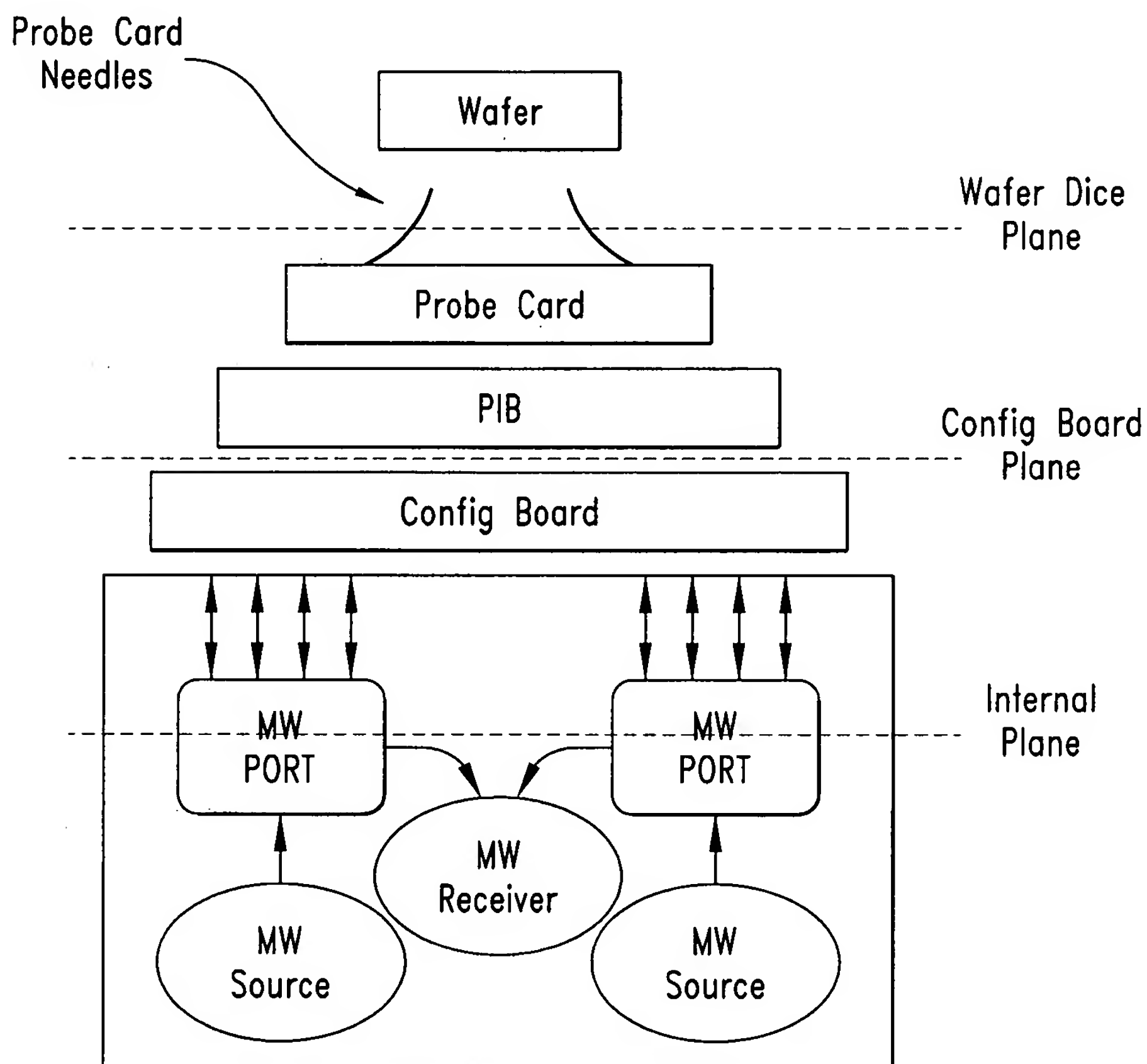
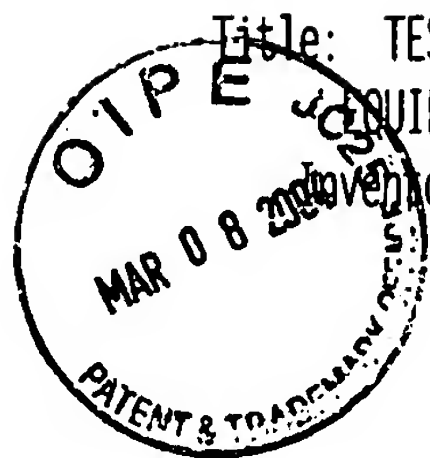


FIG. 2
(Prior Art)

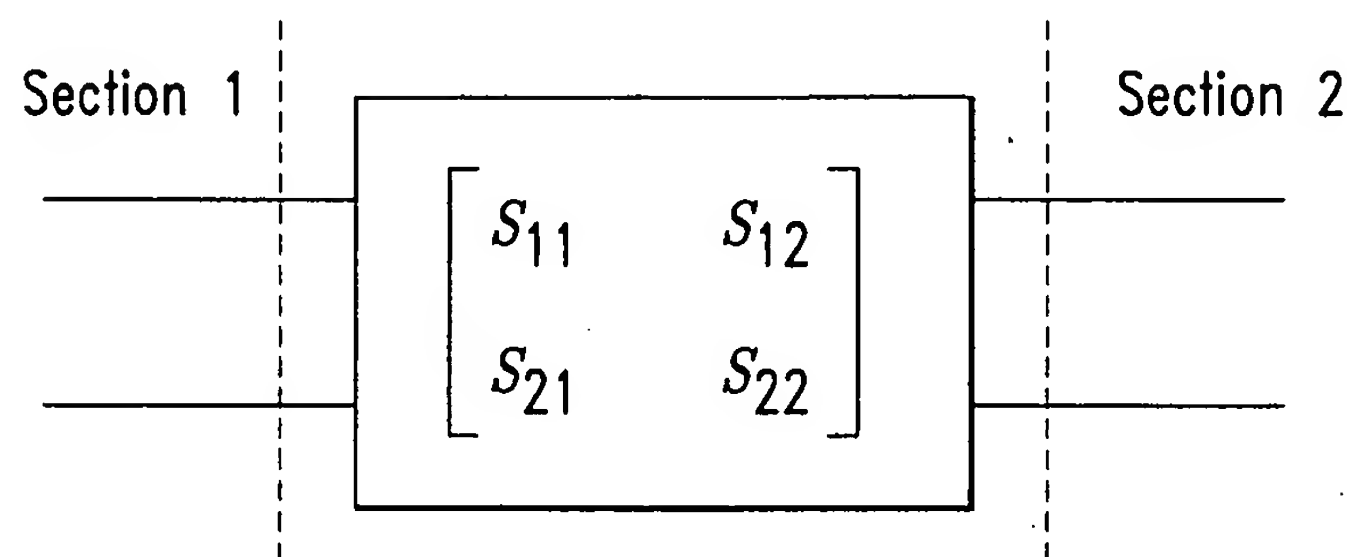


FIG. 3

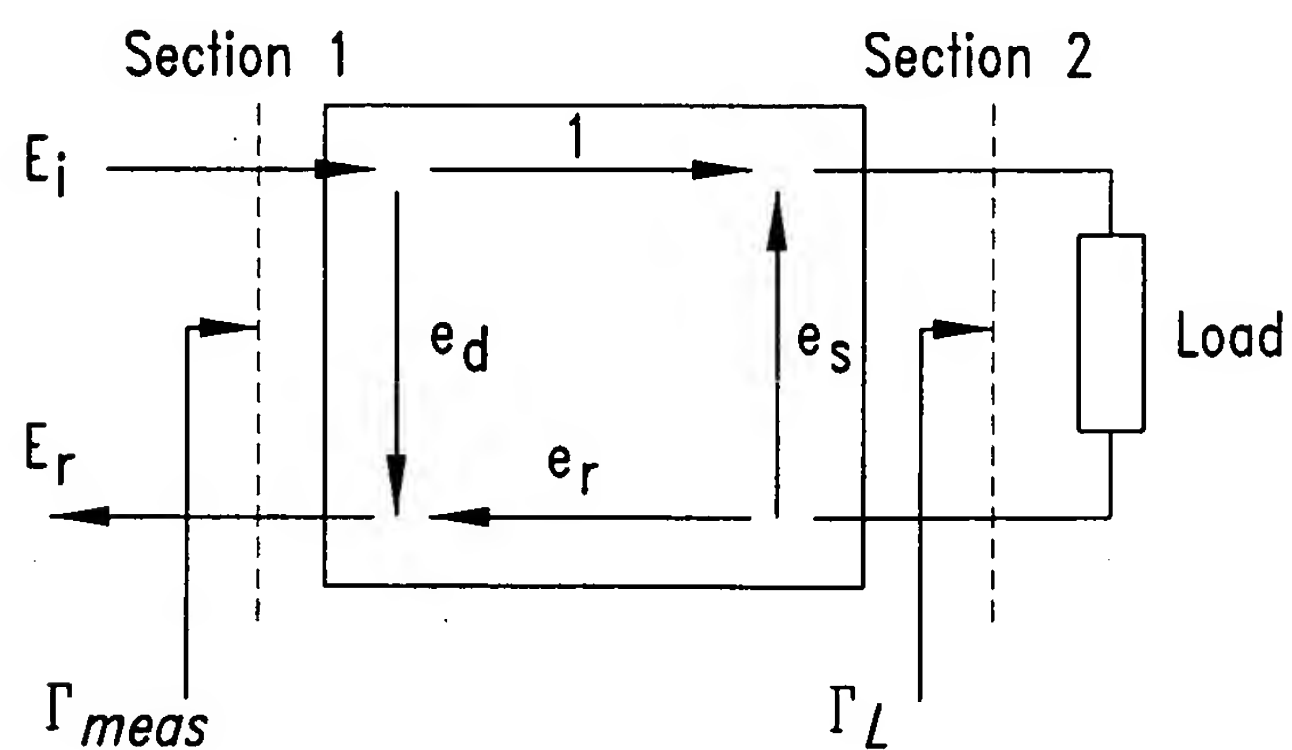


FIG. 4

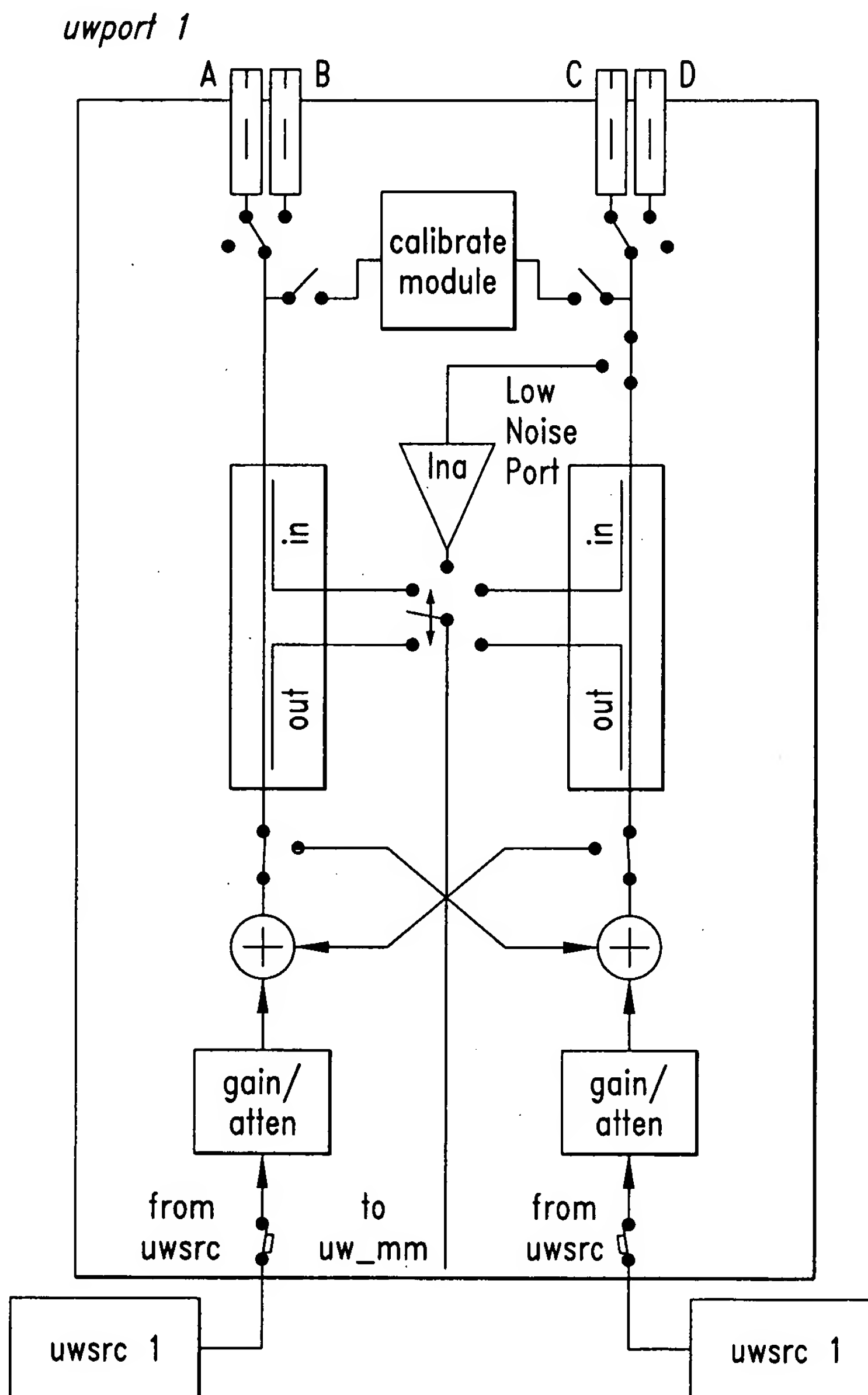
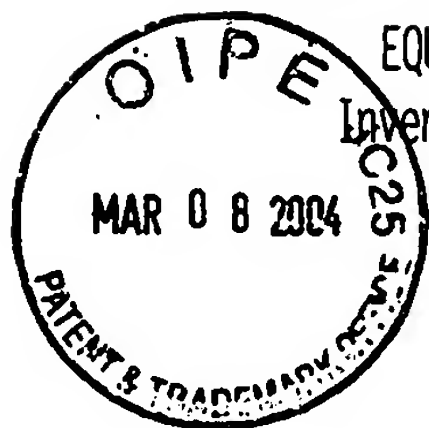
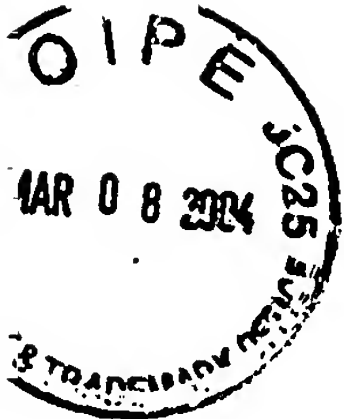


FIG. 5



Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"
Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678

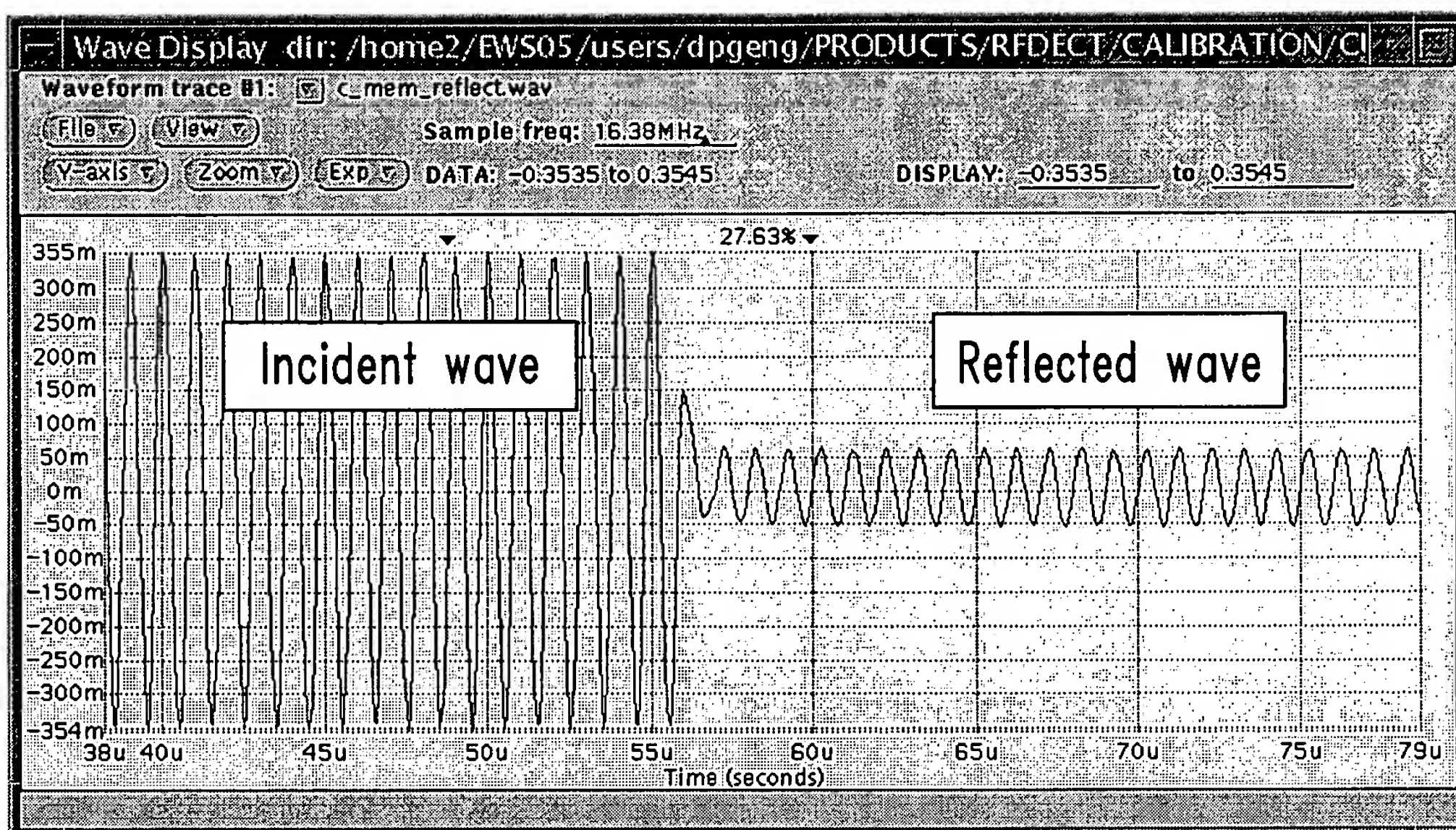


FIG. 6



Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING
EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"
Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678

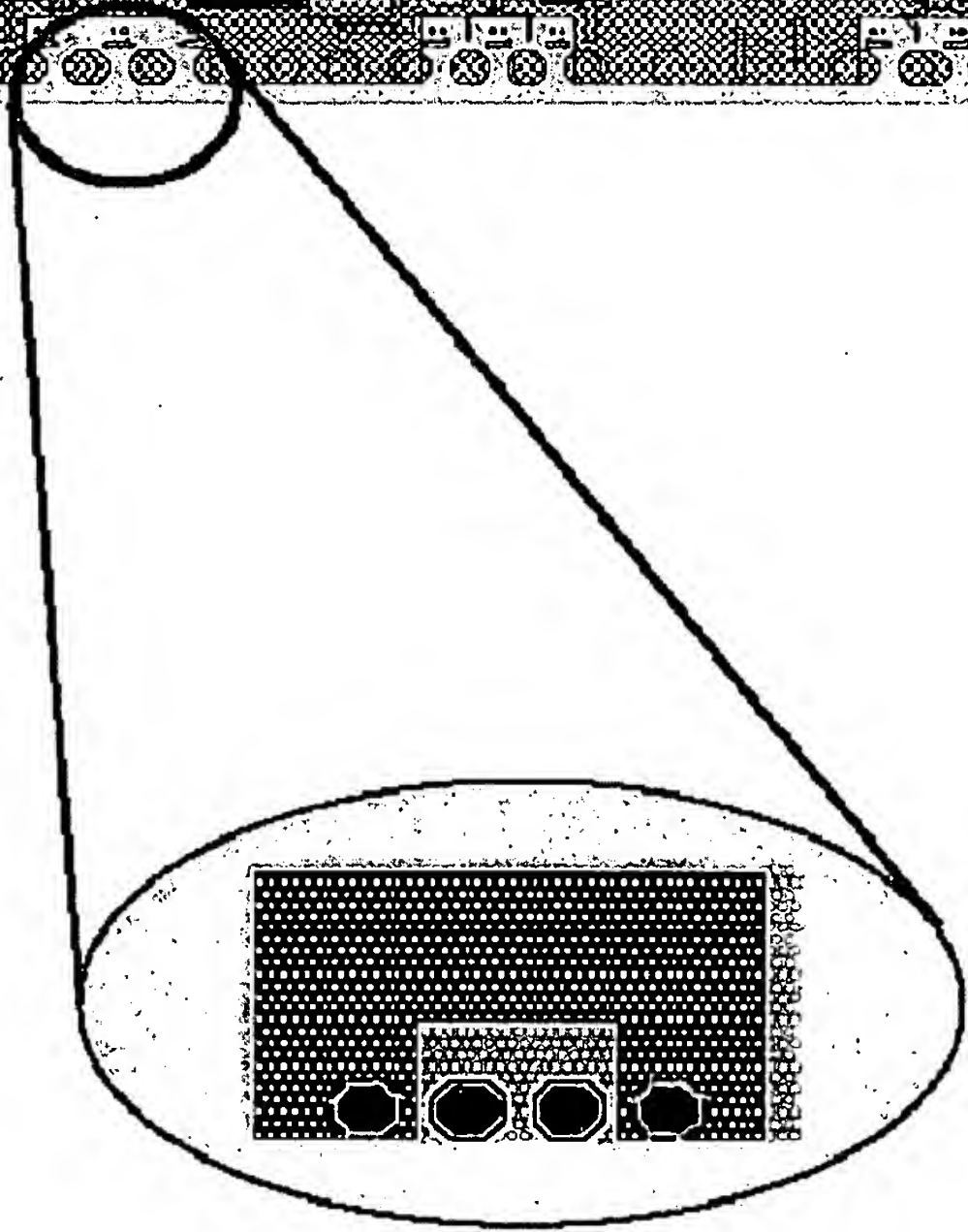
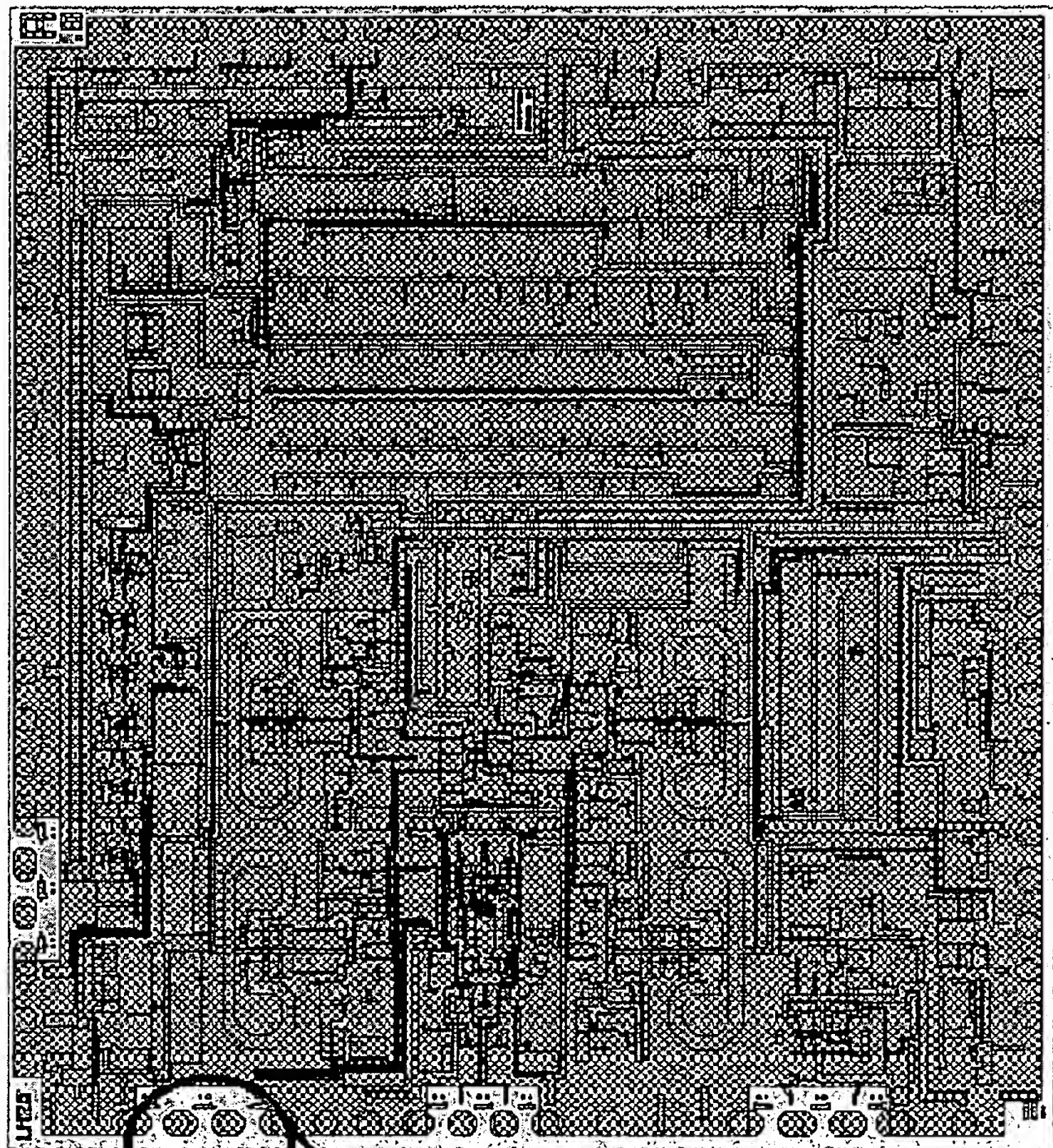


FIG. 7



Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING
EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"
Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678

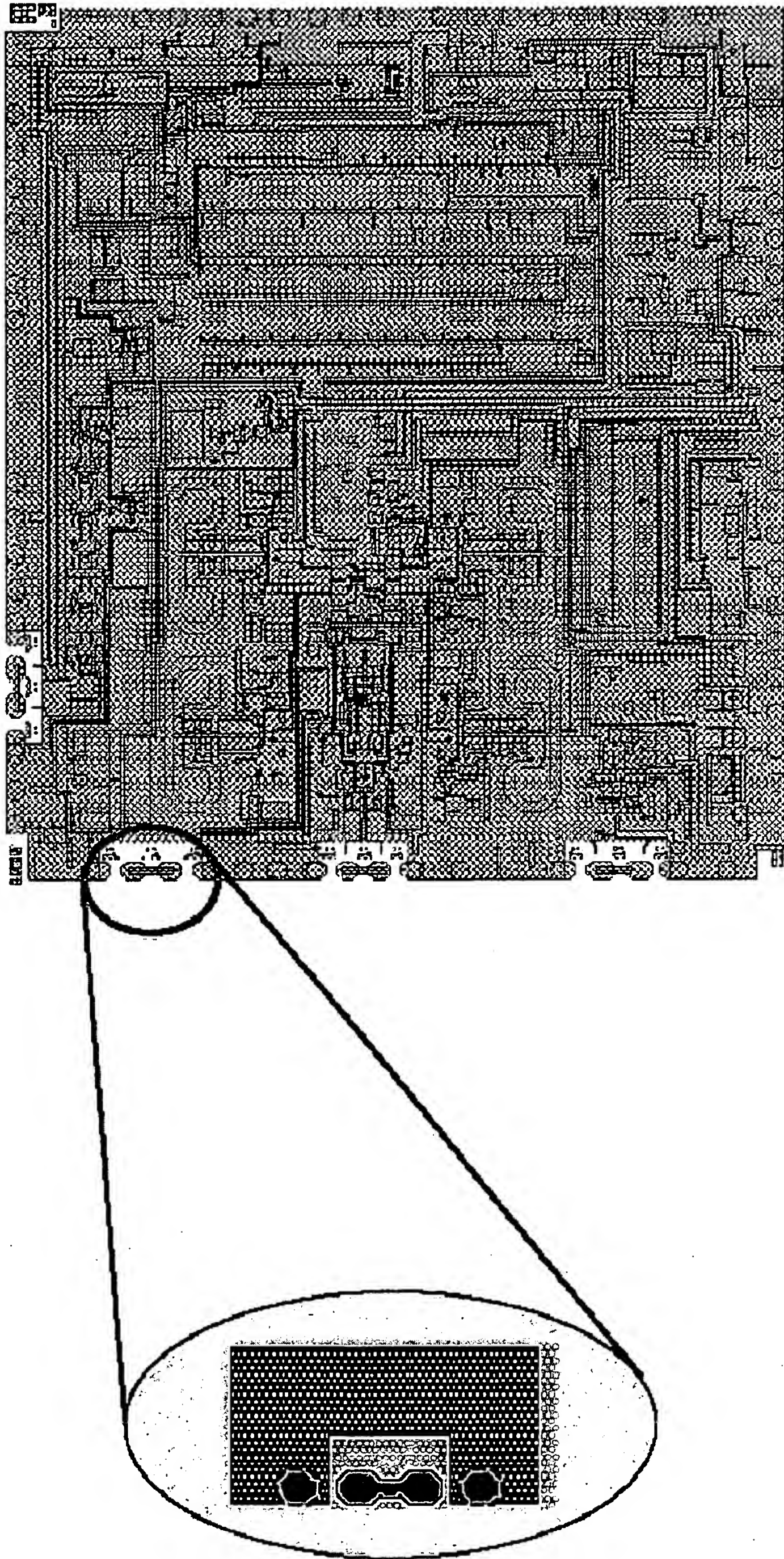
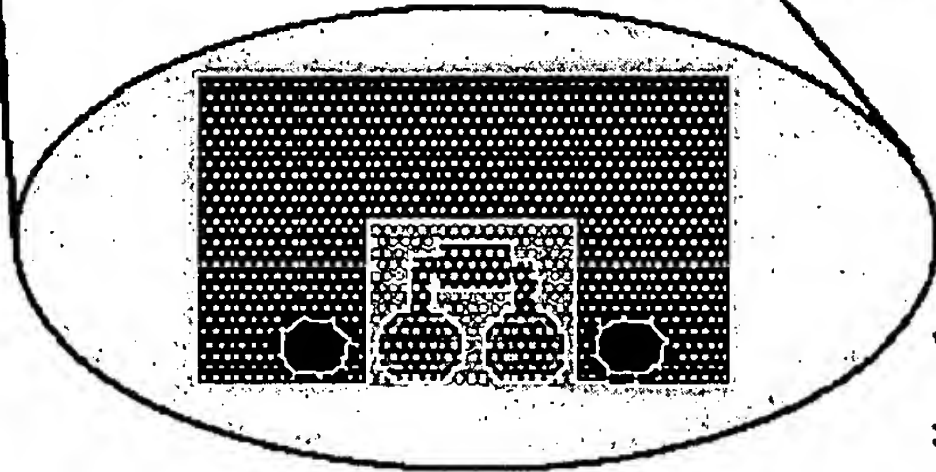
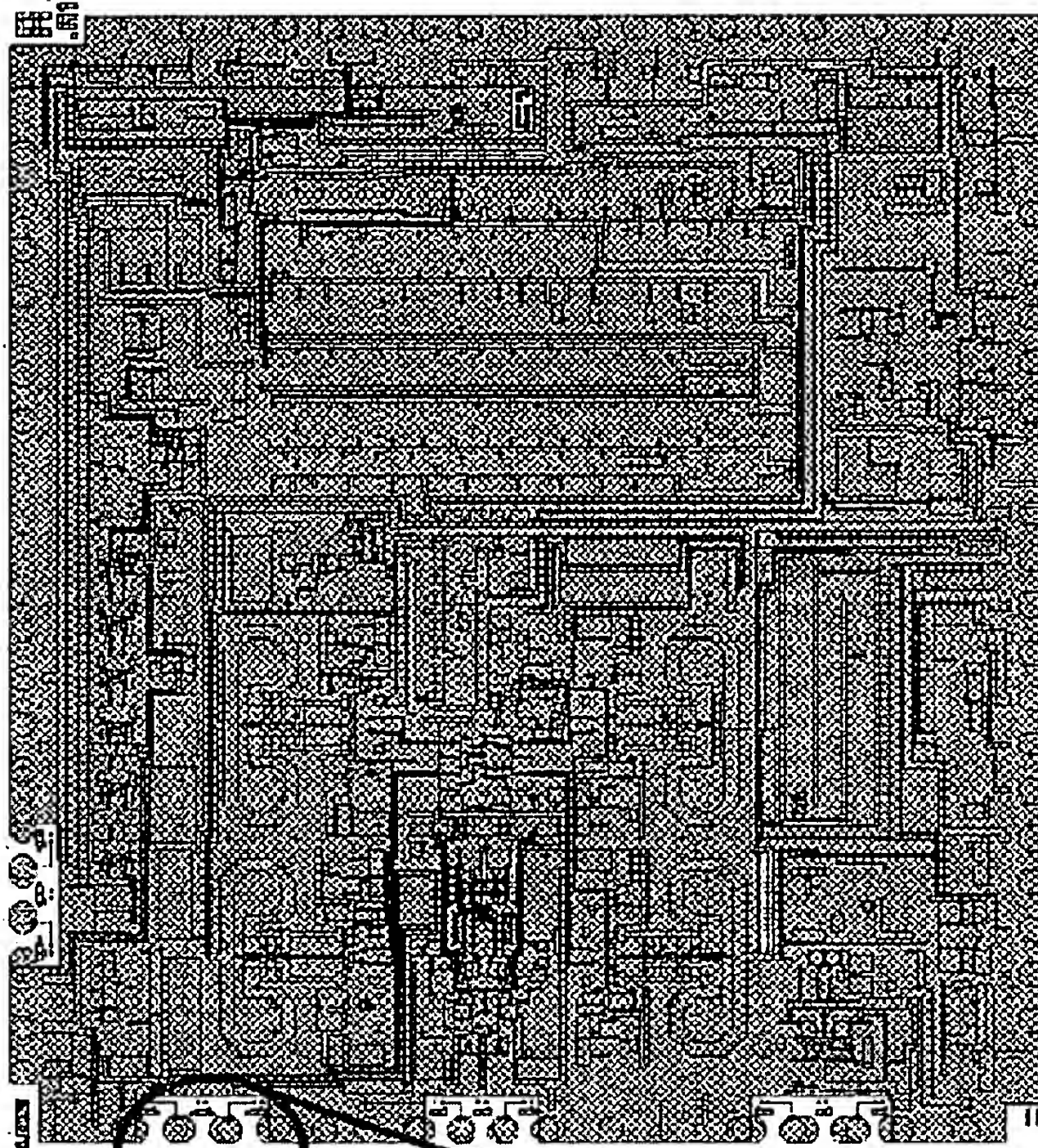


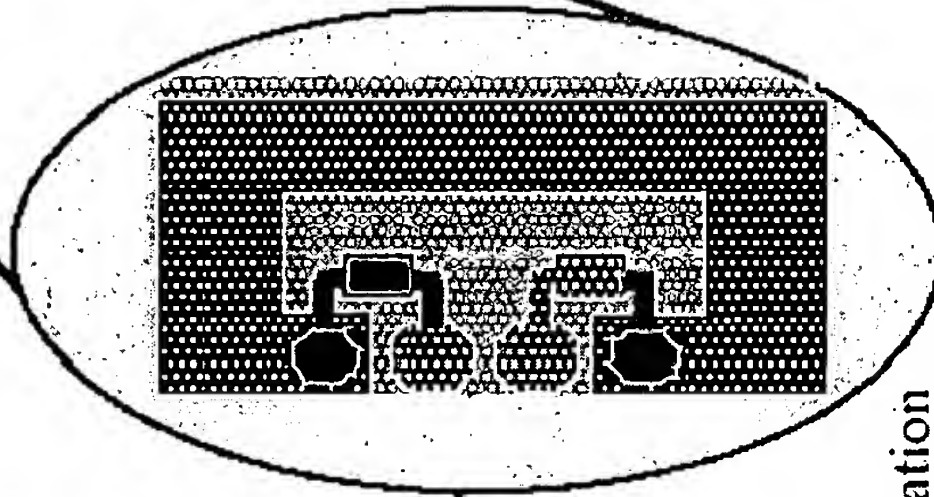
FIG. 8



Title: TEST BOARD DE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY ON AN AUTOMATIC TESTING EQUIPMENT FOR IC WAFERS Express Mail No. EV336594715US "REPLACEMENT SHEET"
Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678



Not Splitted
Configuration



Splitted
Configuration

FIG. 9

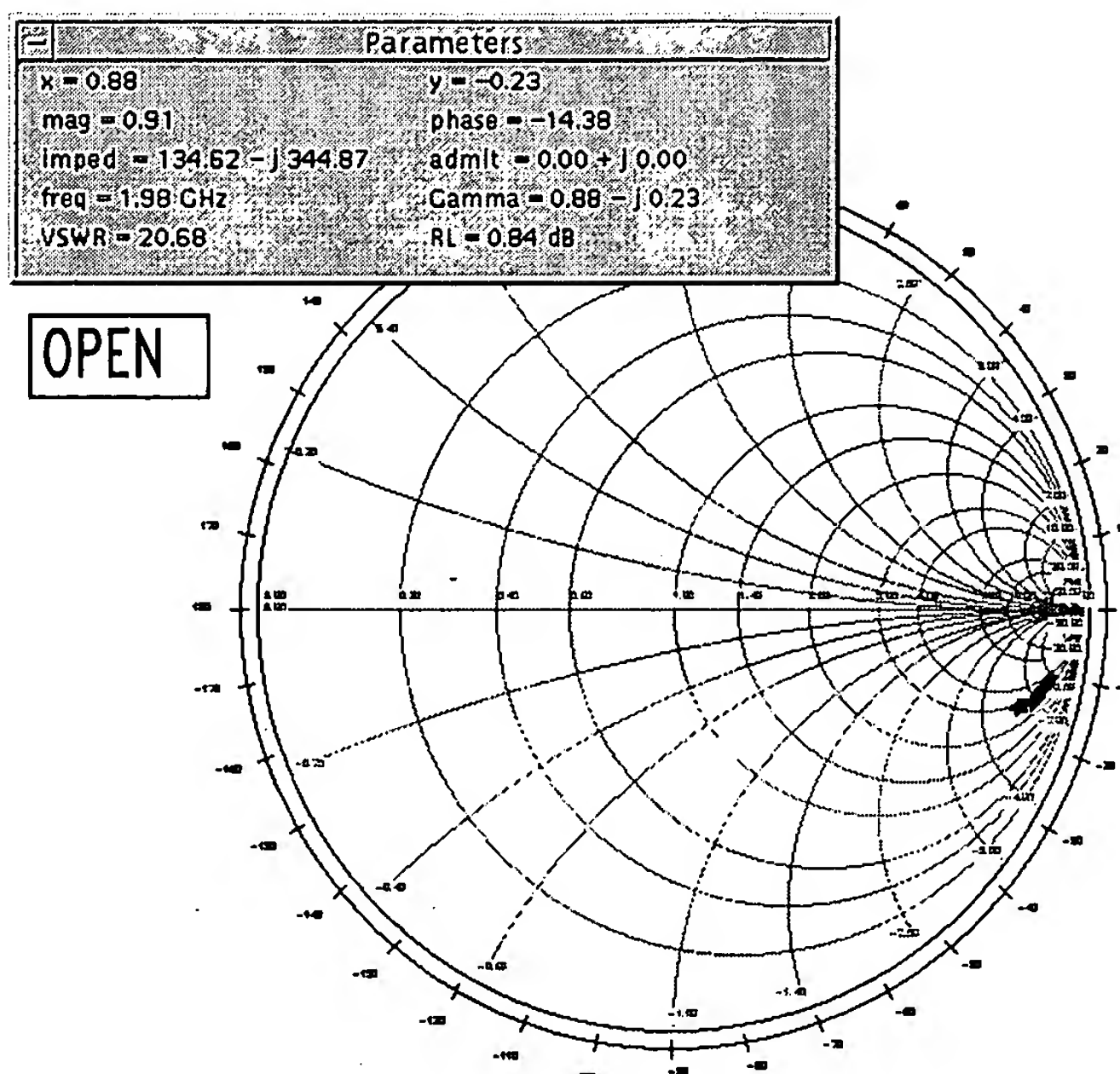


FIG. 10

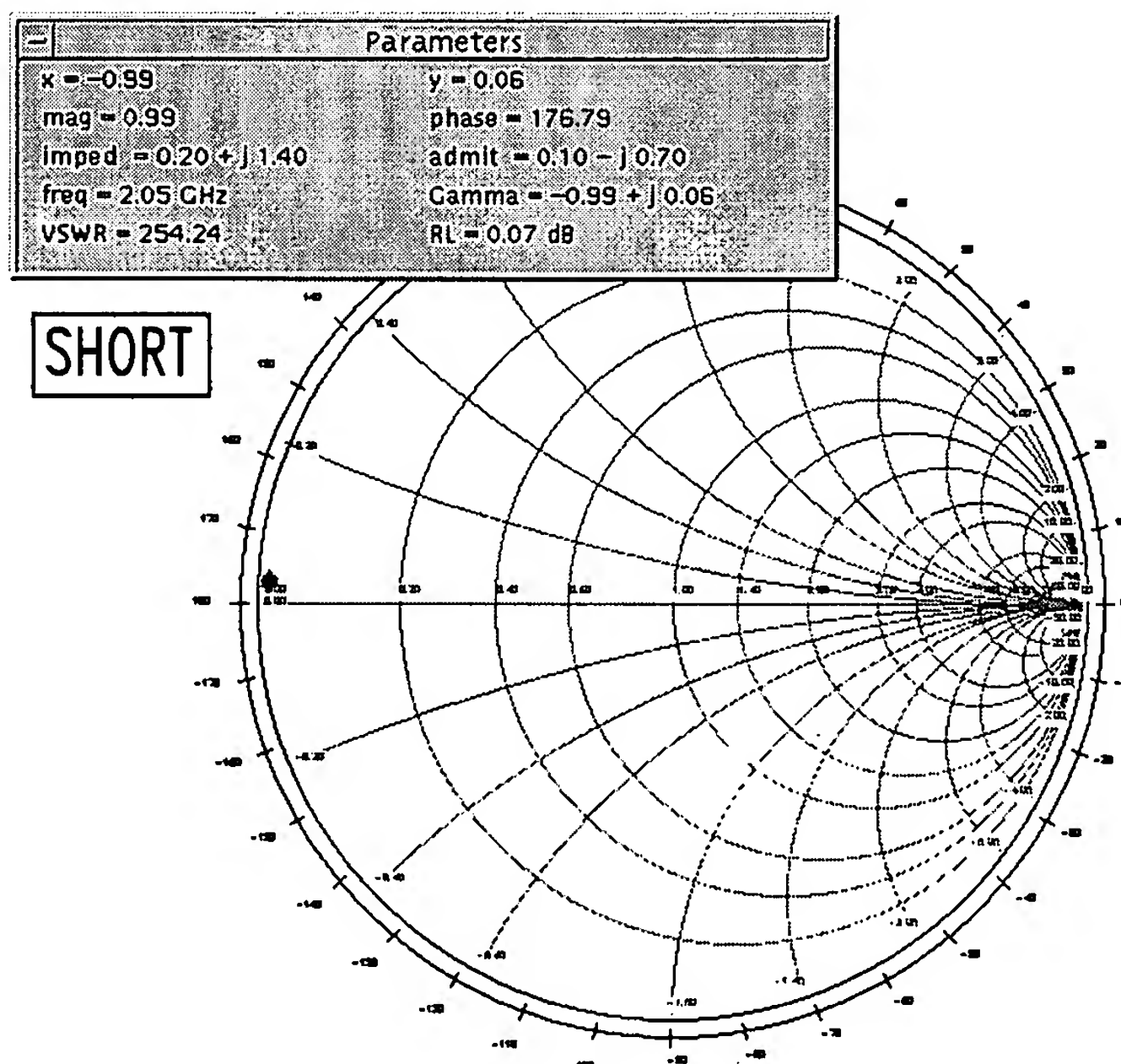


FIG. 11

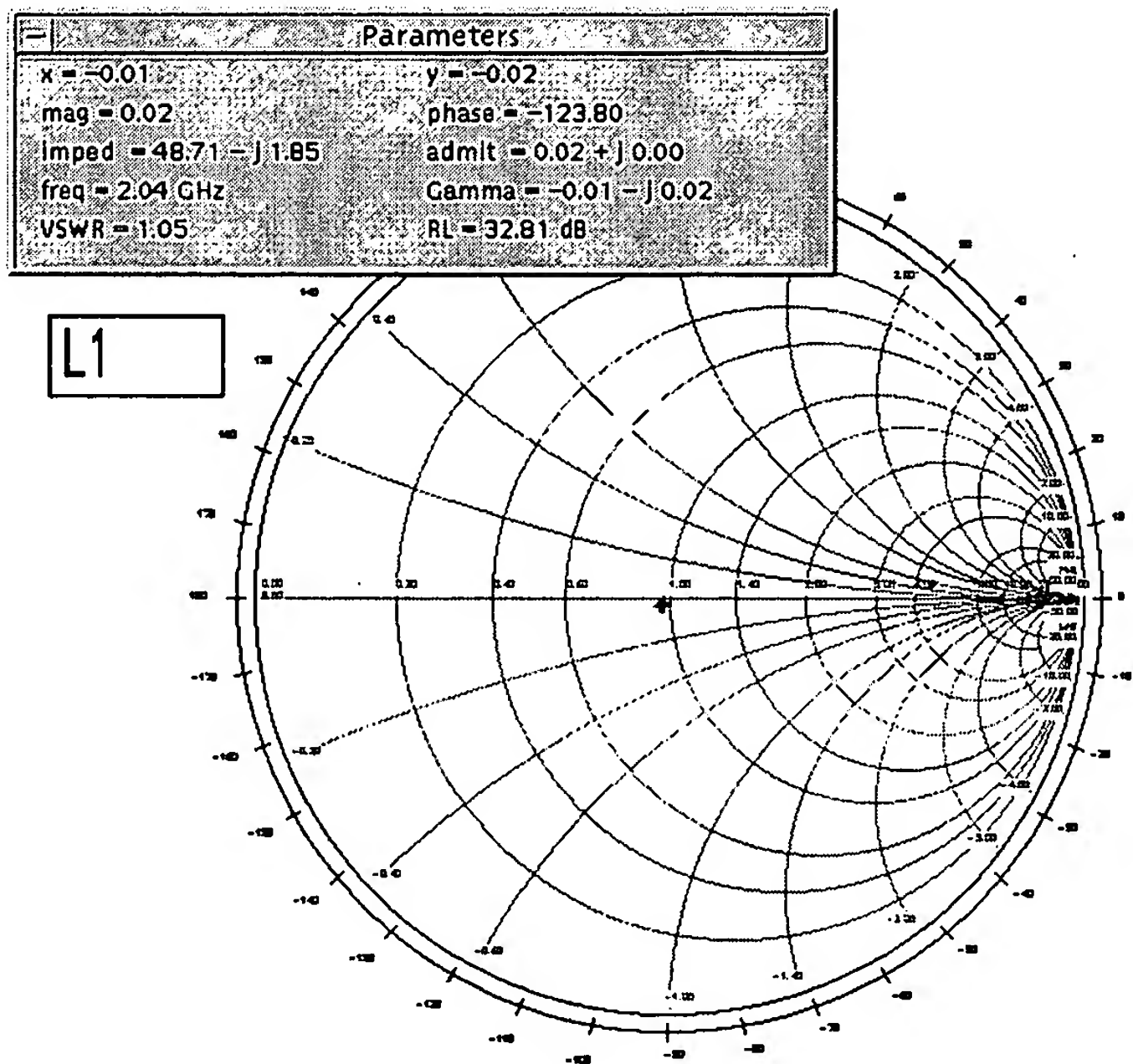


FIG. 12

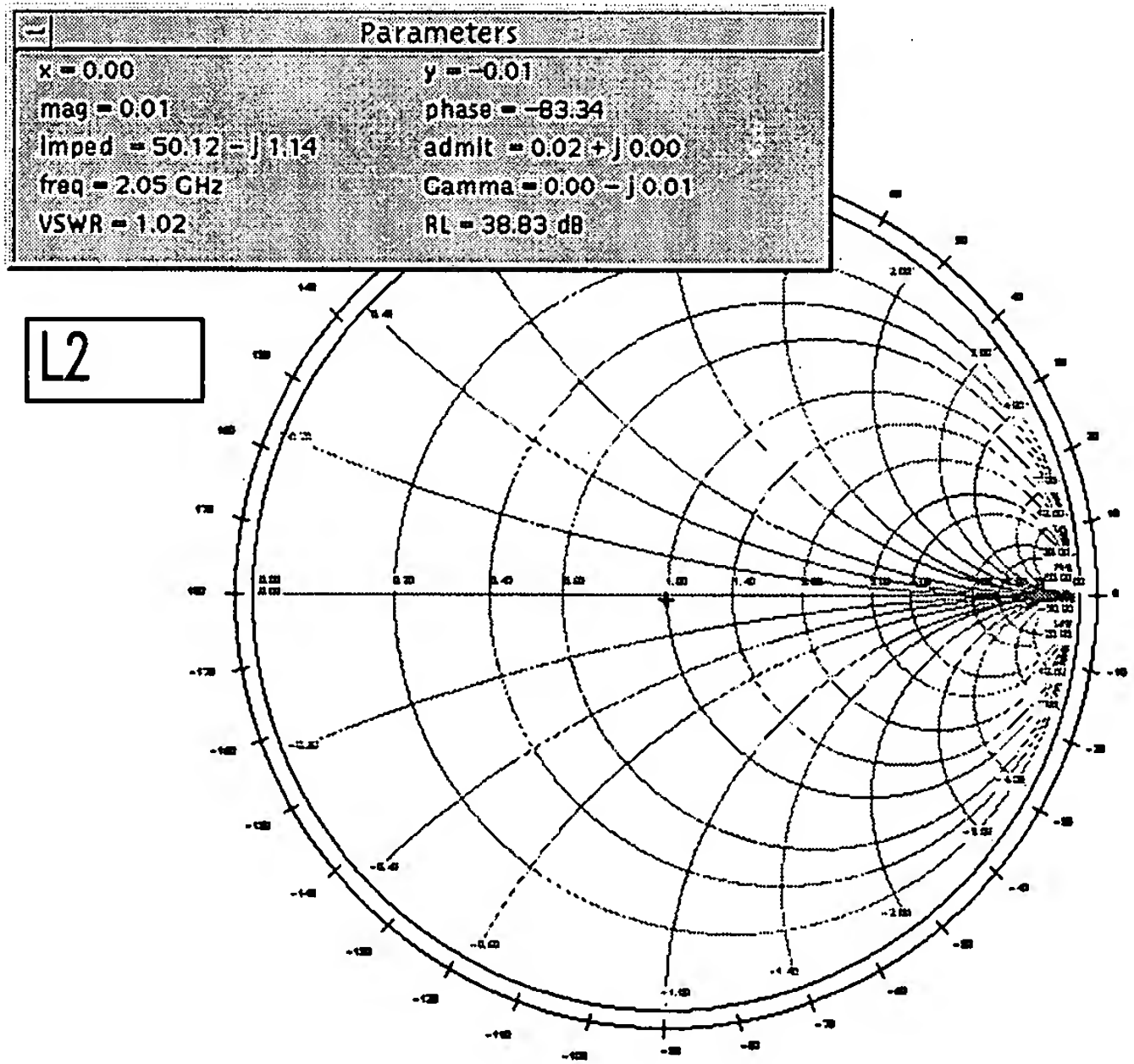


FIG. 13

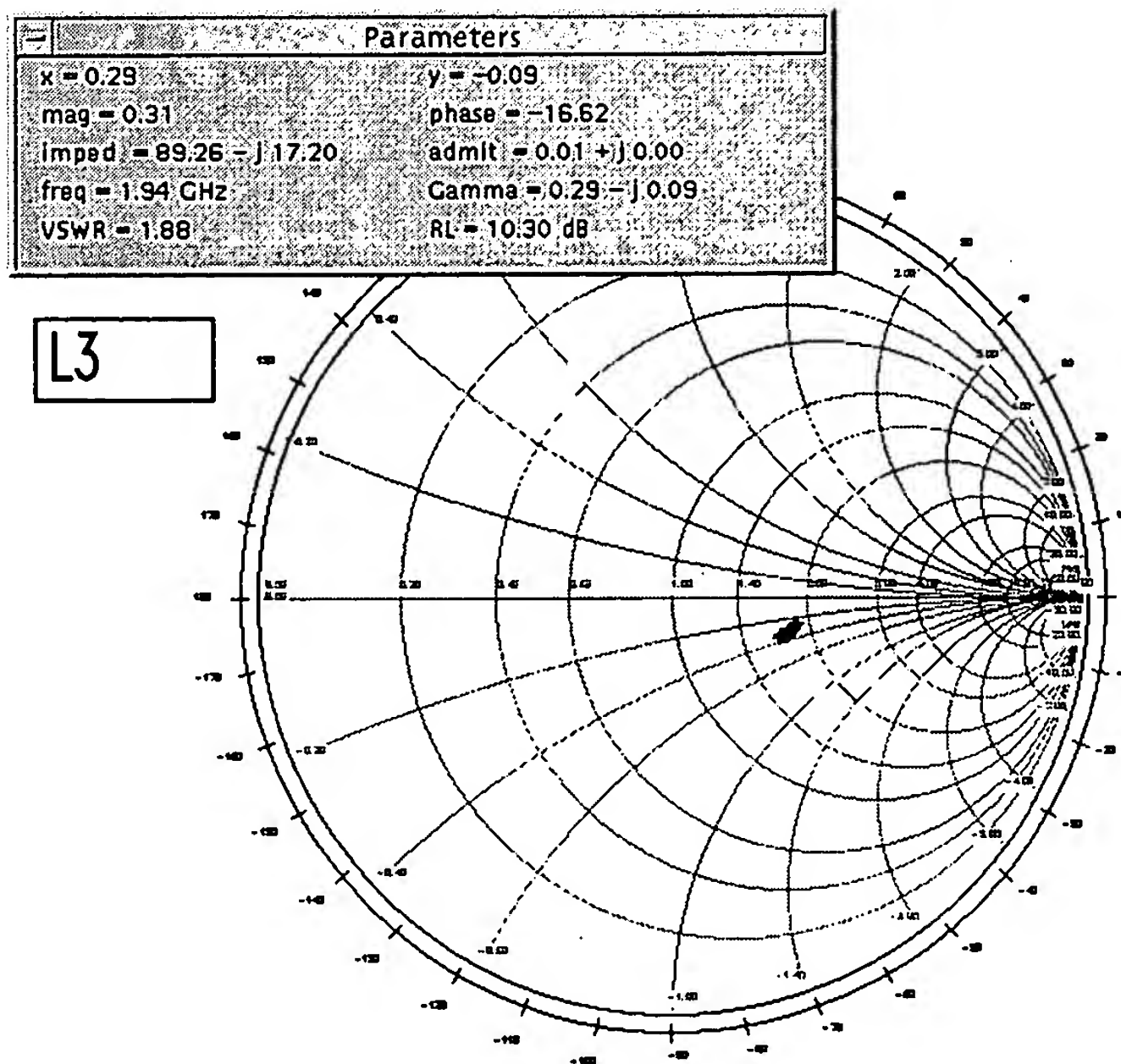


FIG. 14

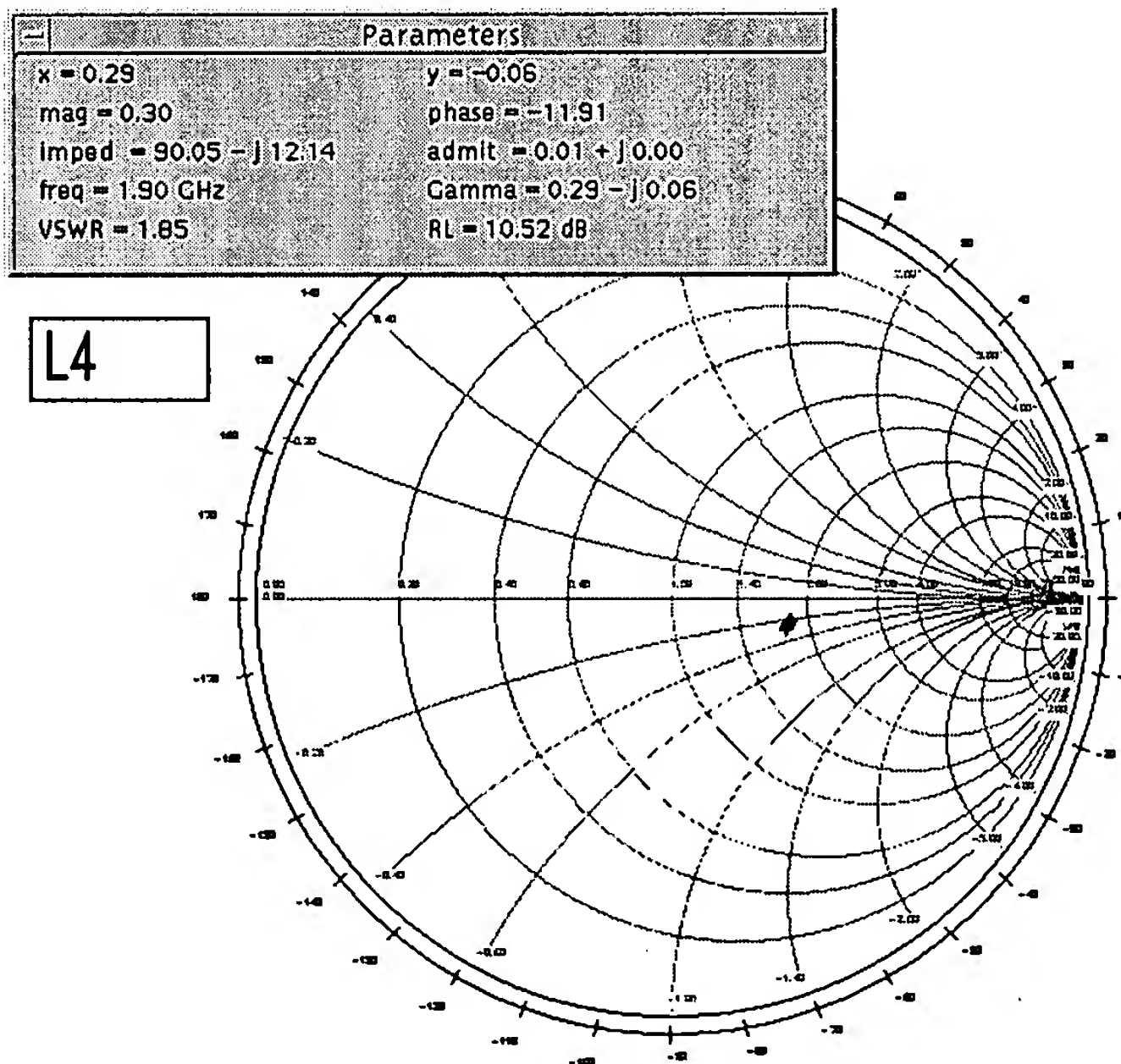


FIG. 15



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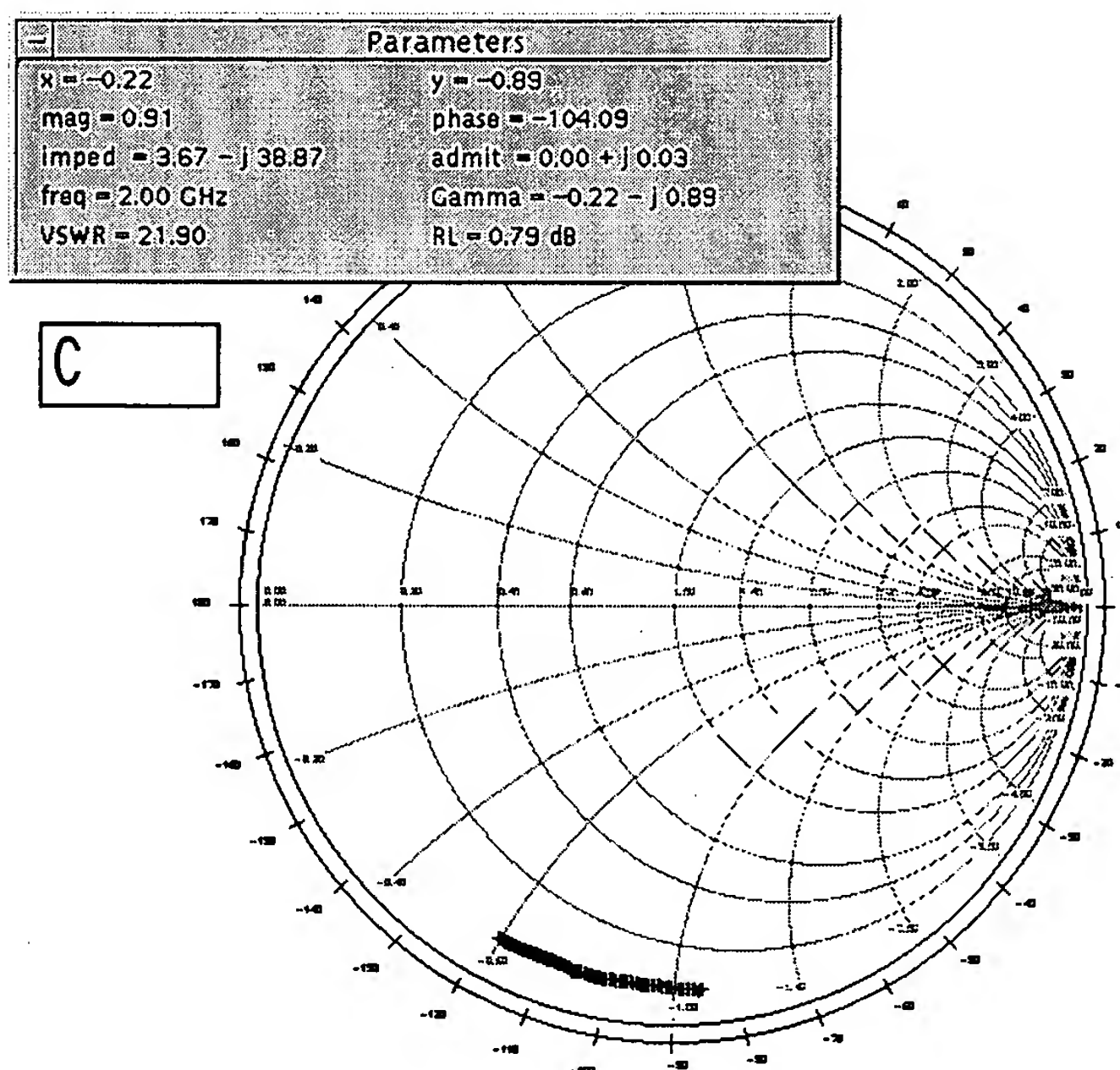


FIG. 16

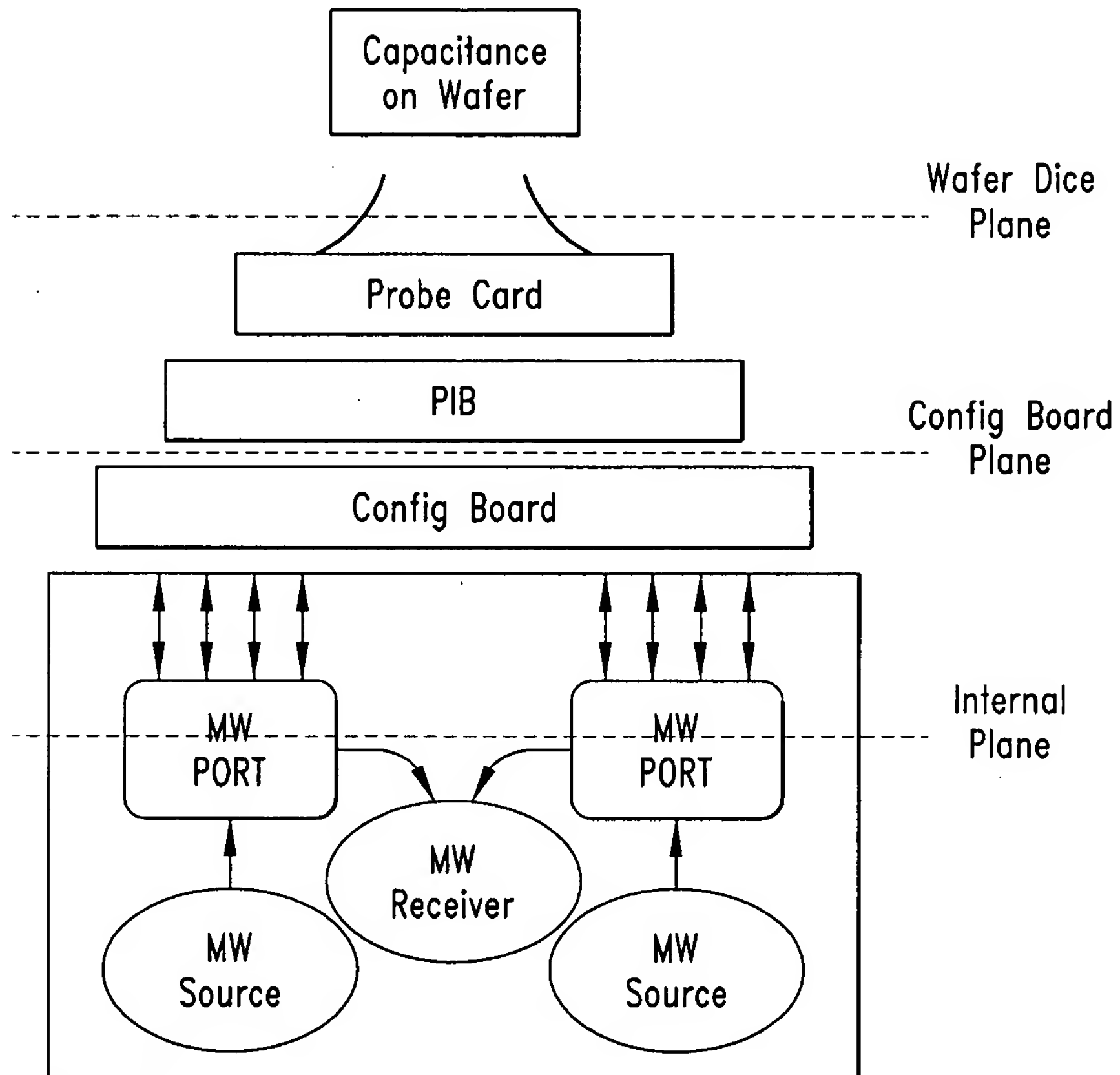


FIG. 17

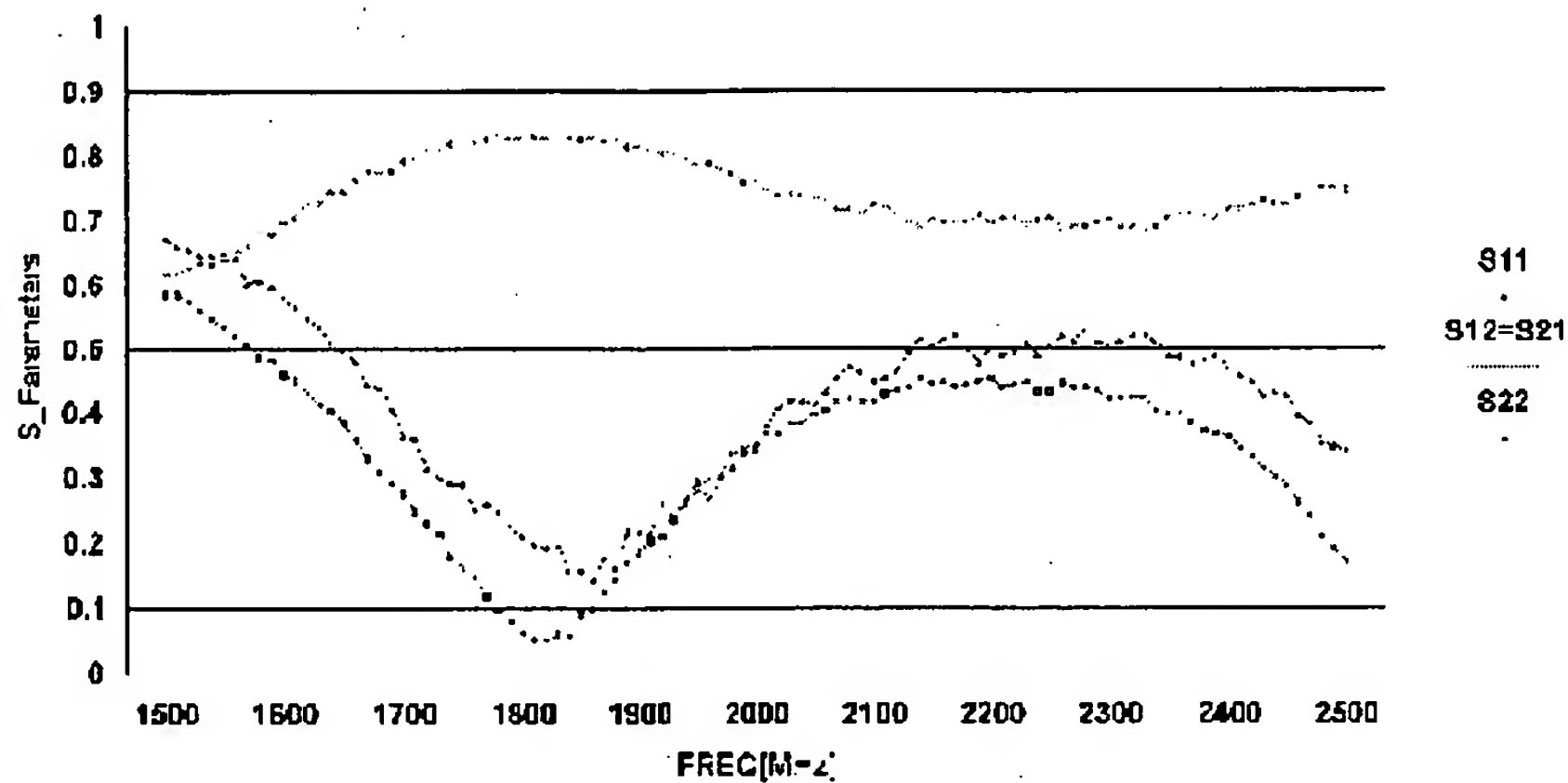


FIG. 18

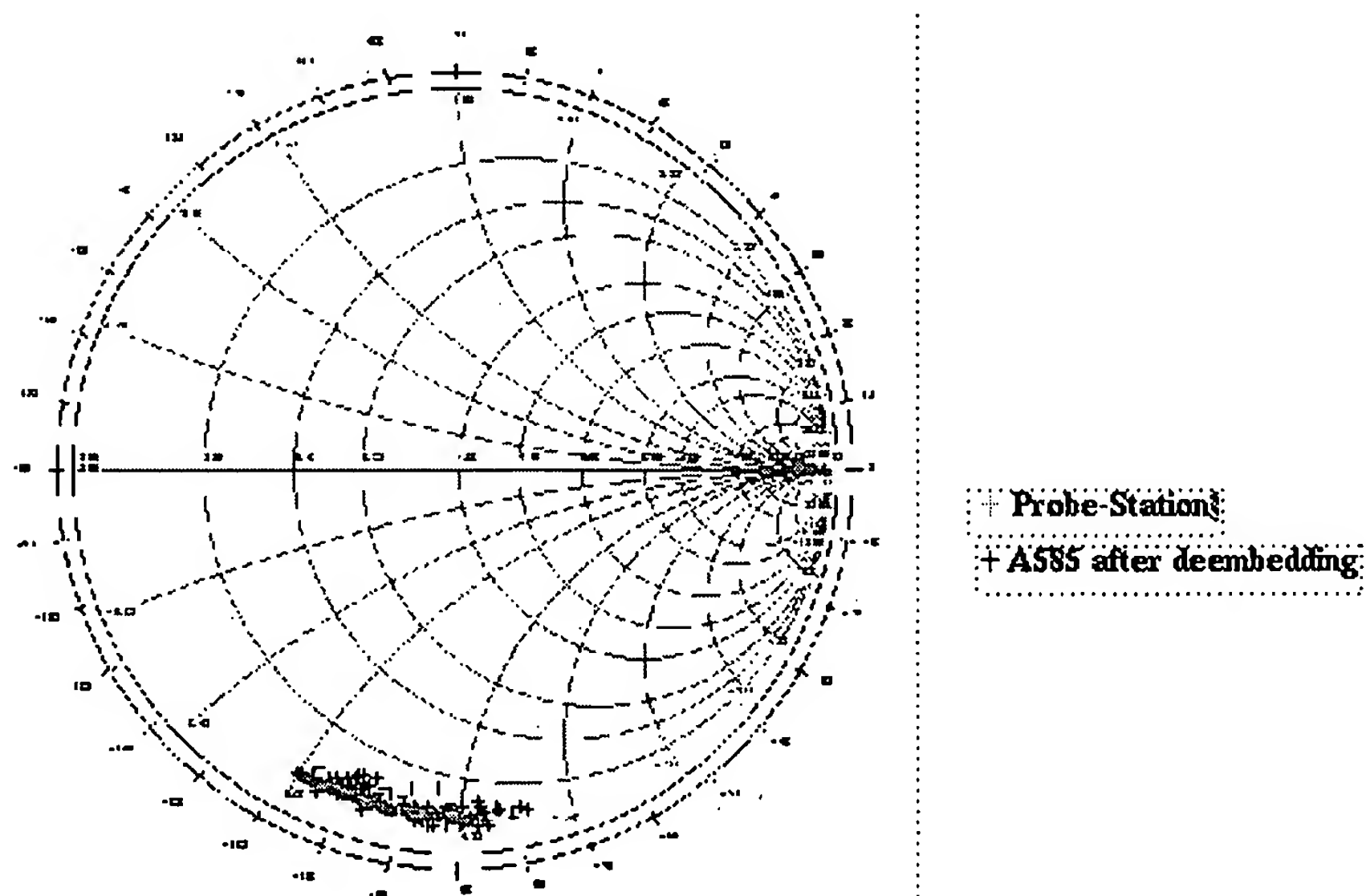


FIG. 19

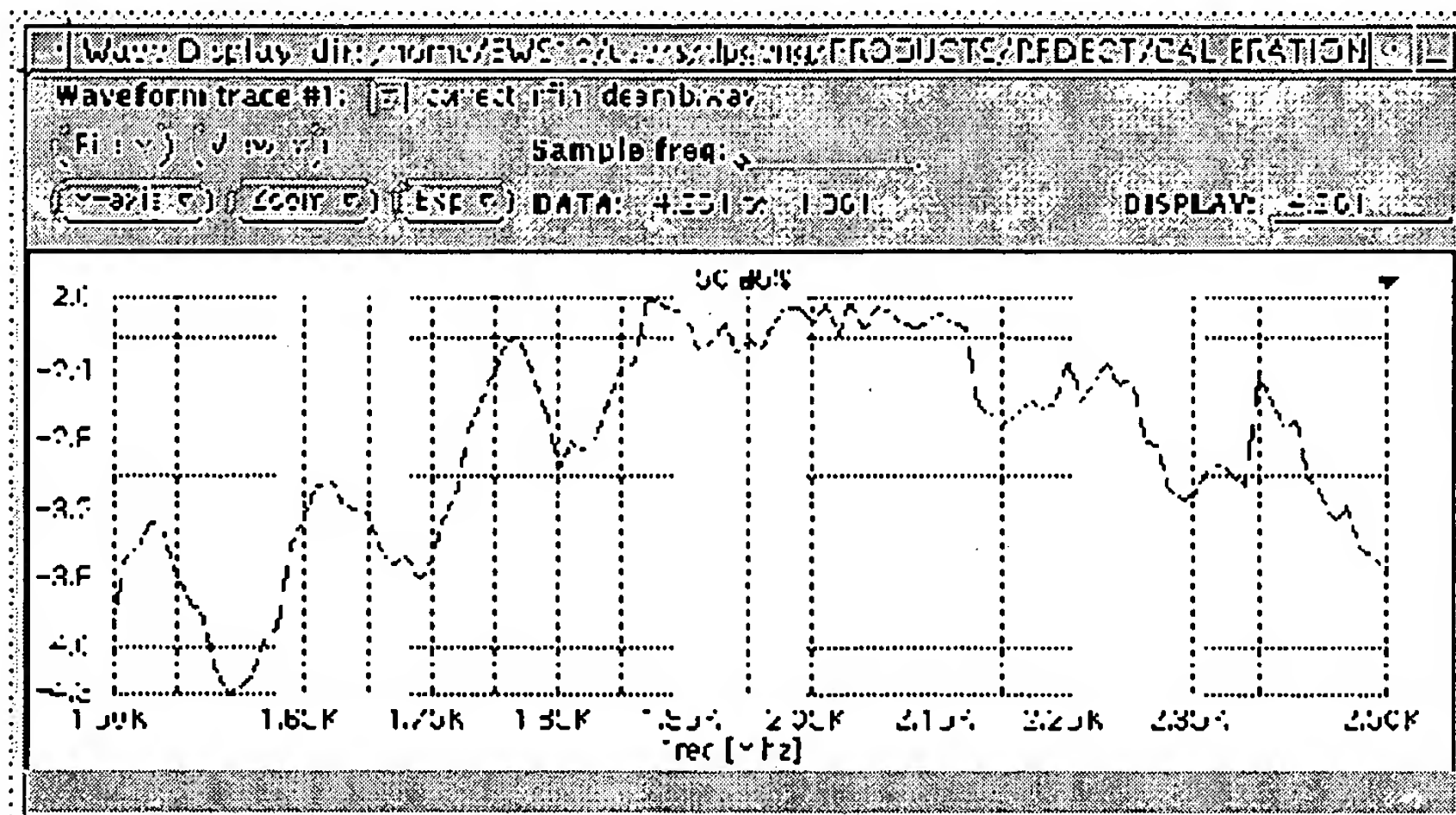


FIG. 20

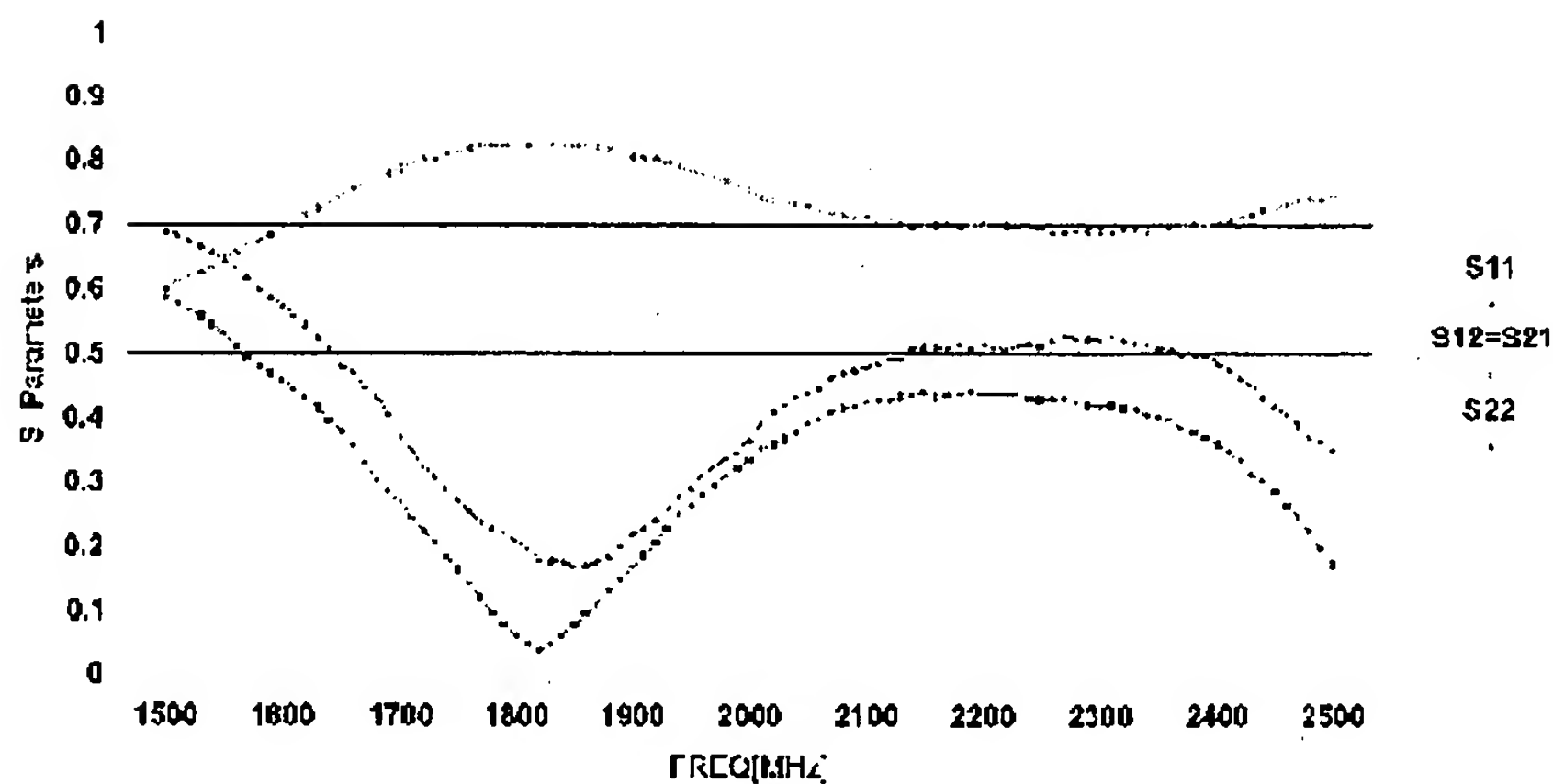


FIG. 21

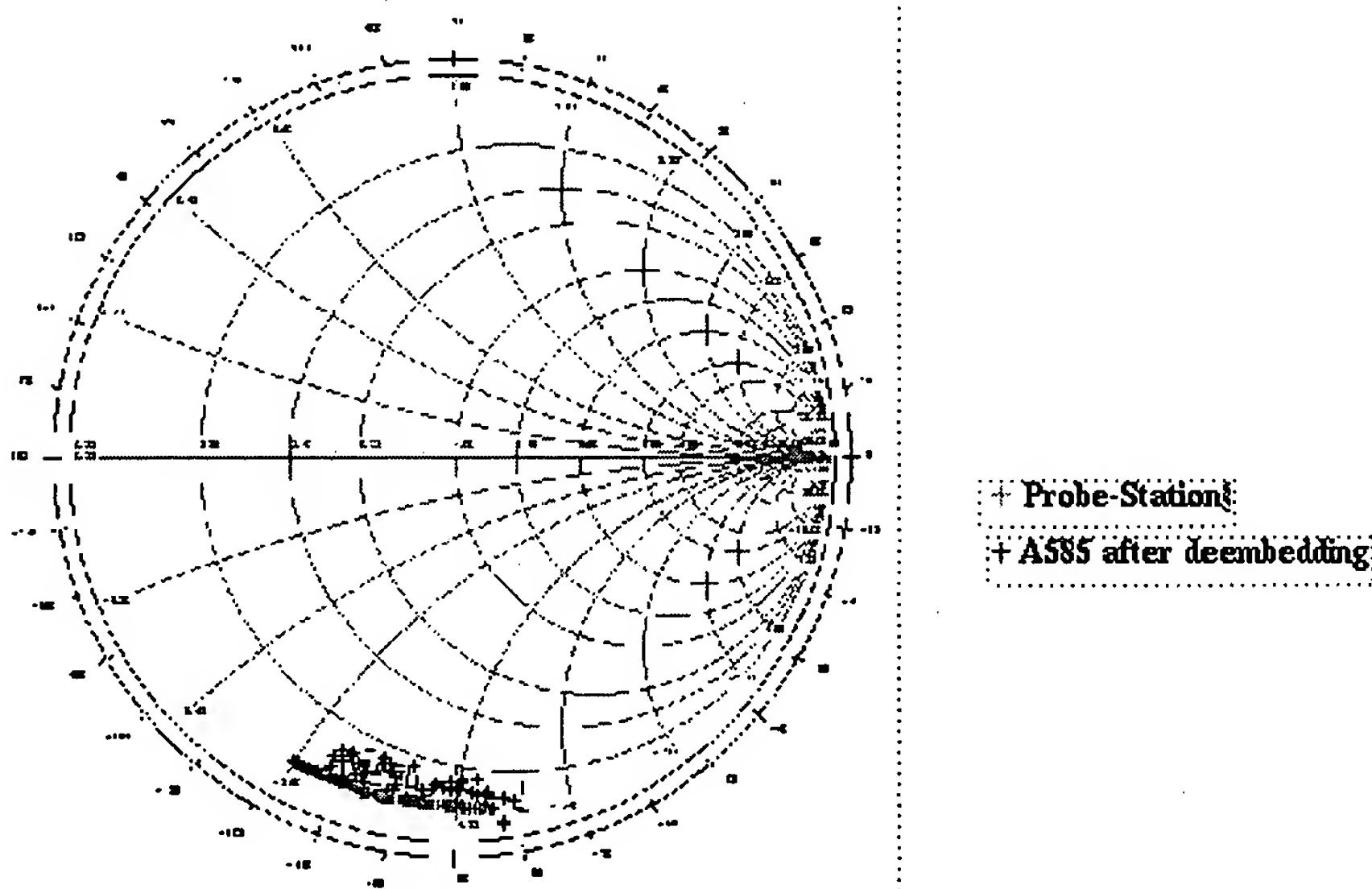


FIG. 22

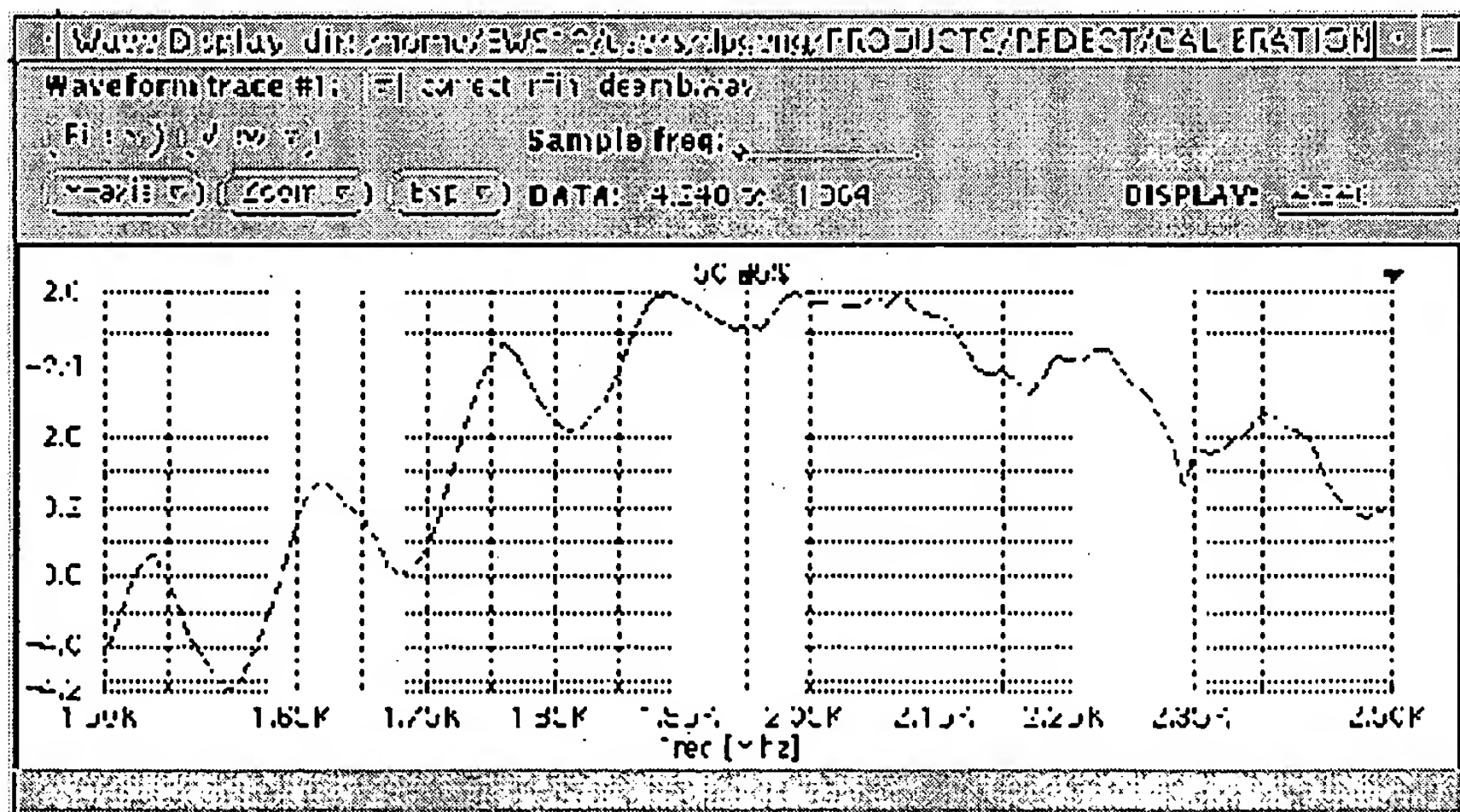


FIG. 23

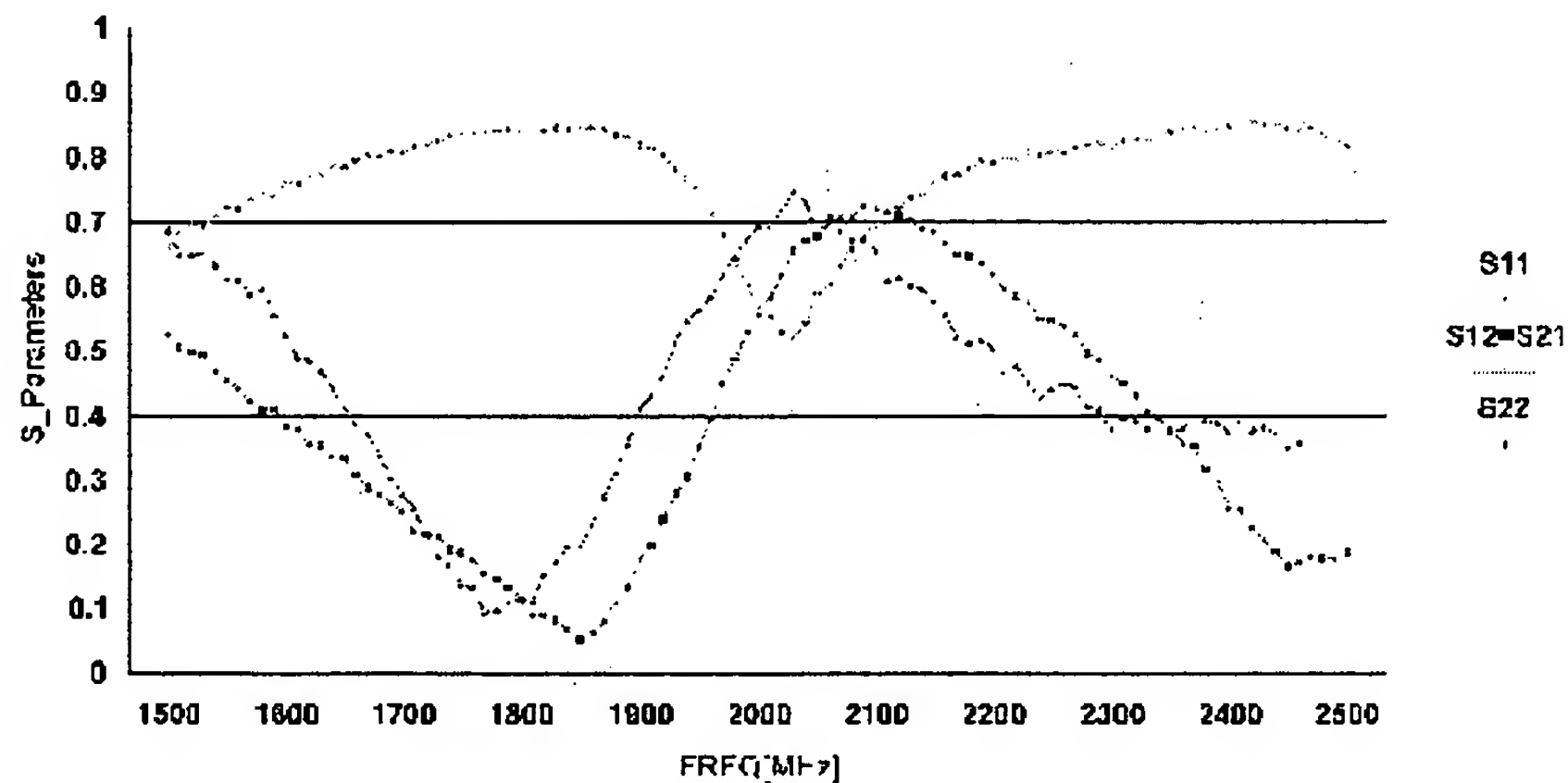


FIG. 24

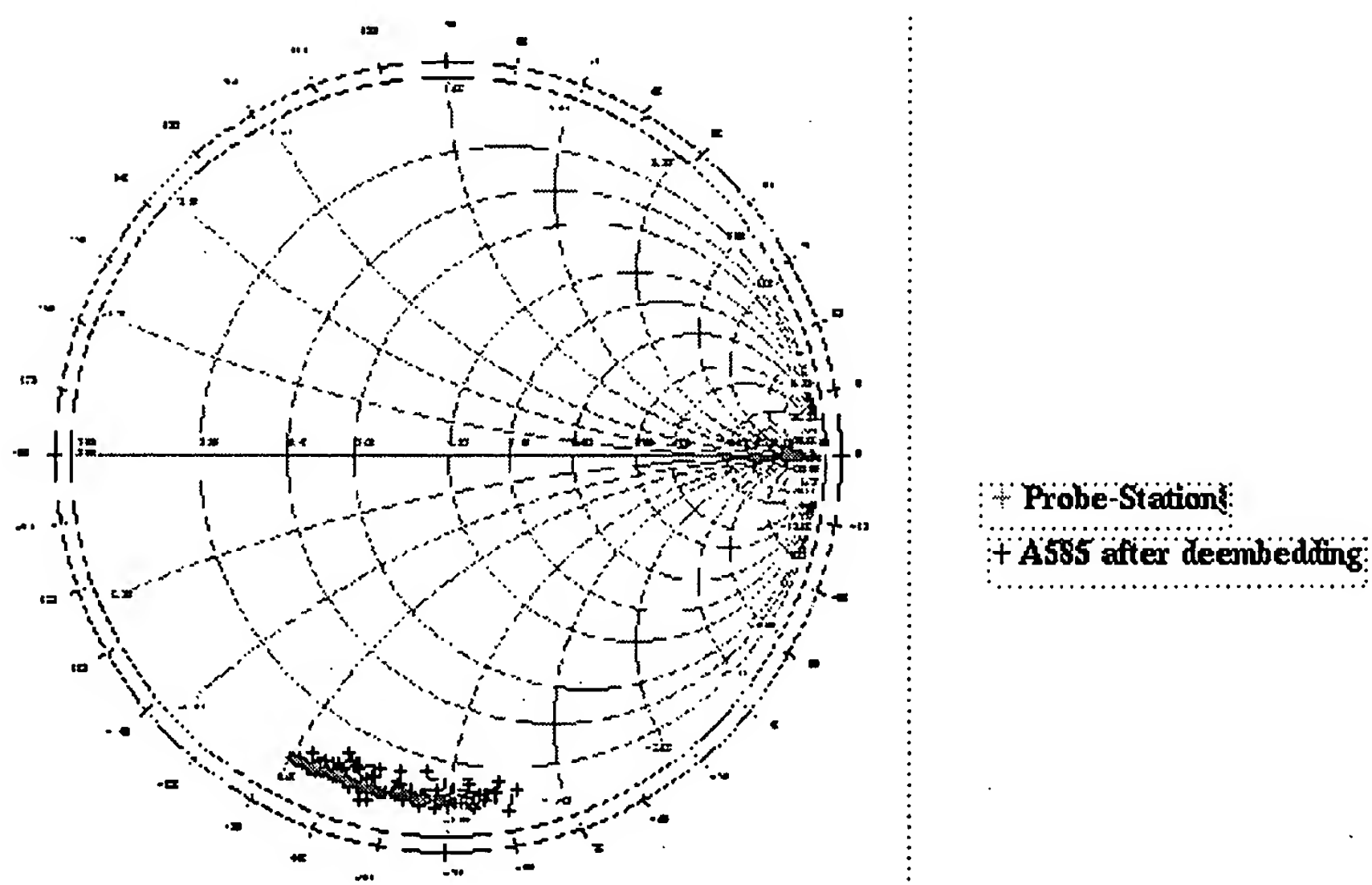


FIG. 25



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Inventor(s): Giuseppe Di Gregorio et al. Serial No. 10/033,364 Docket No. 856063.678

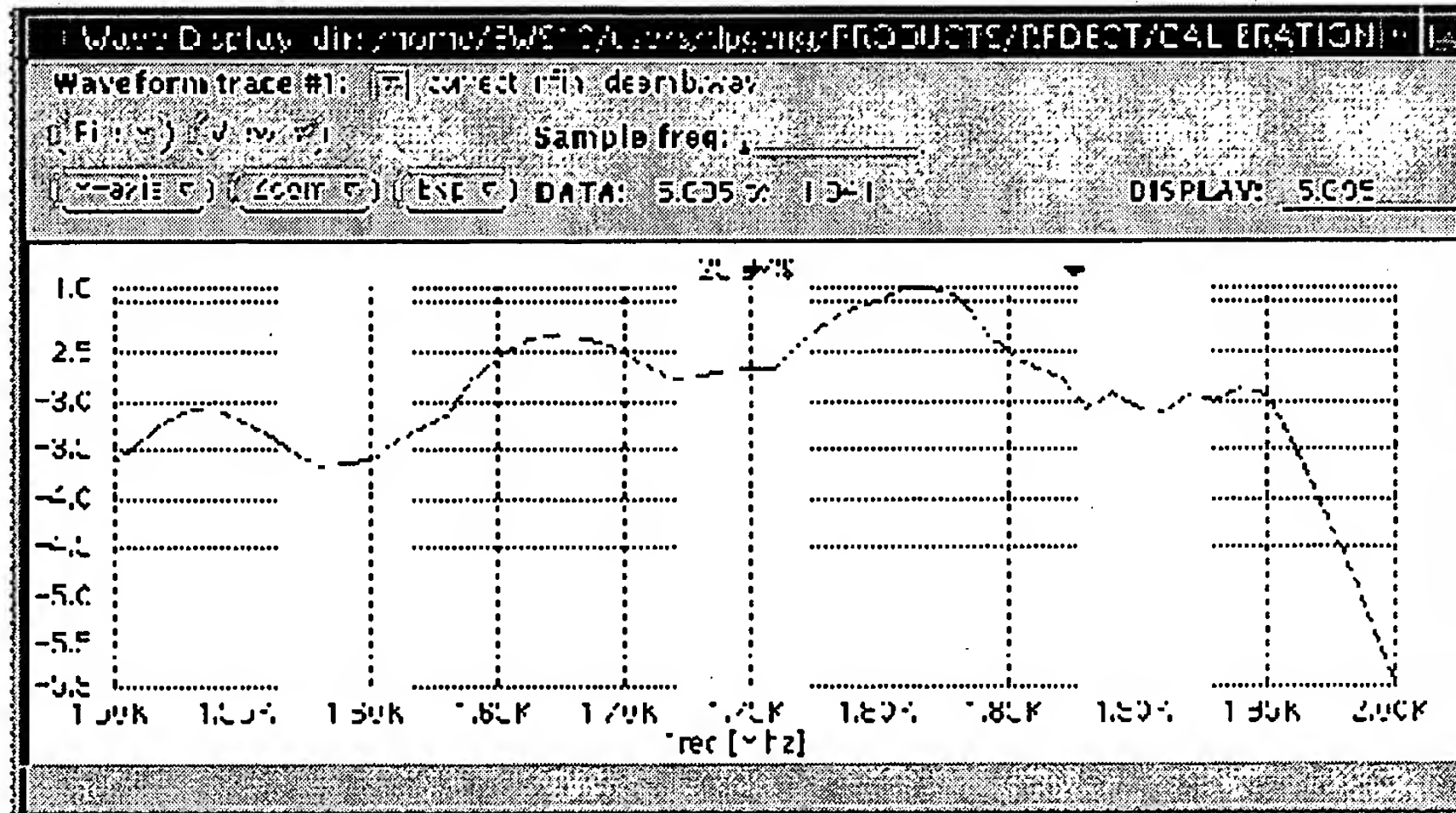


FIG. 26

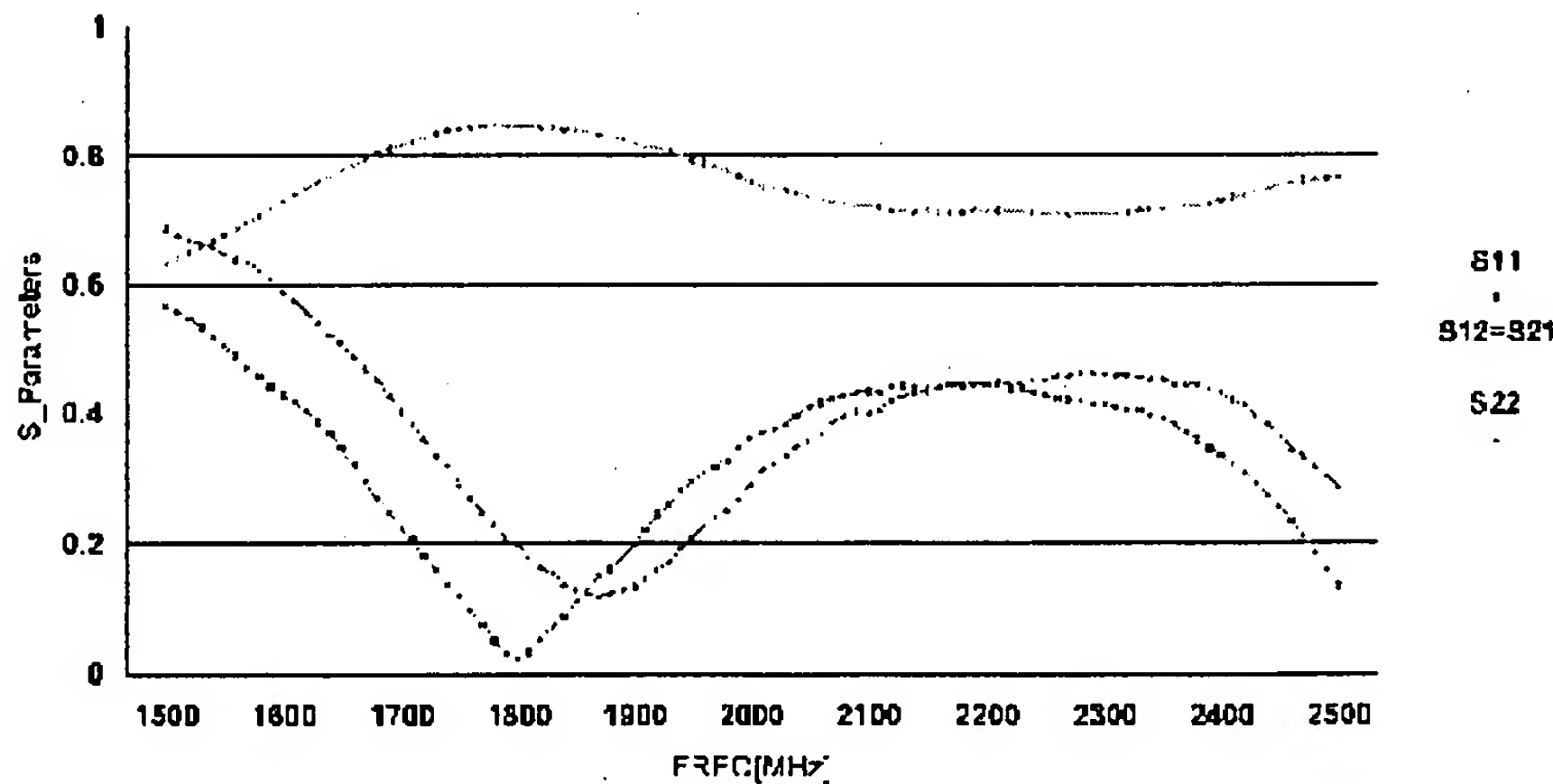


FIG. 27

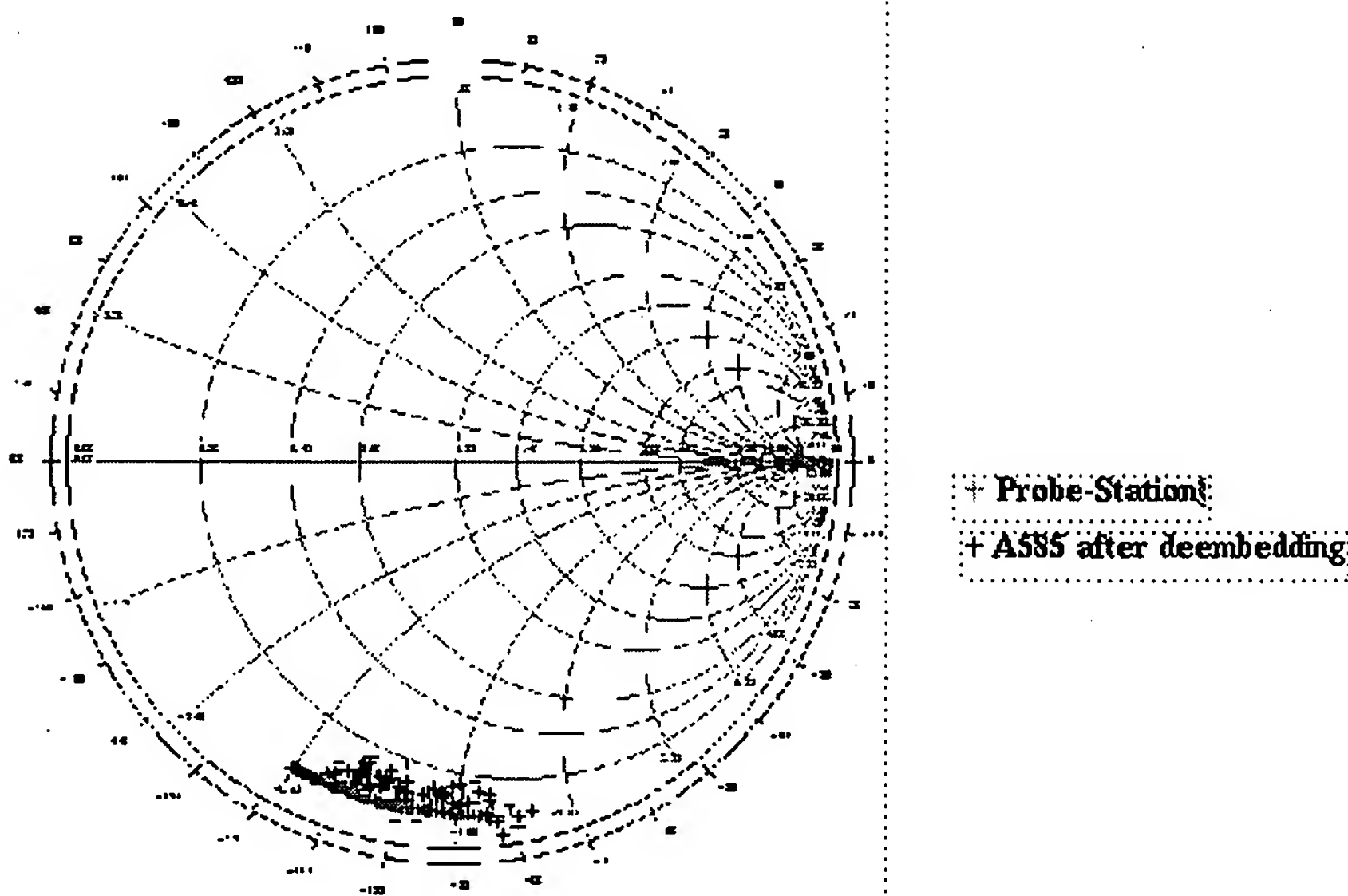


FIG. 28

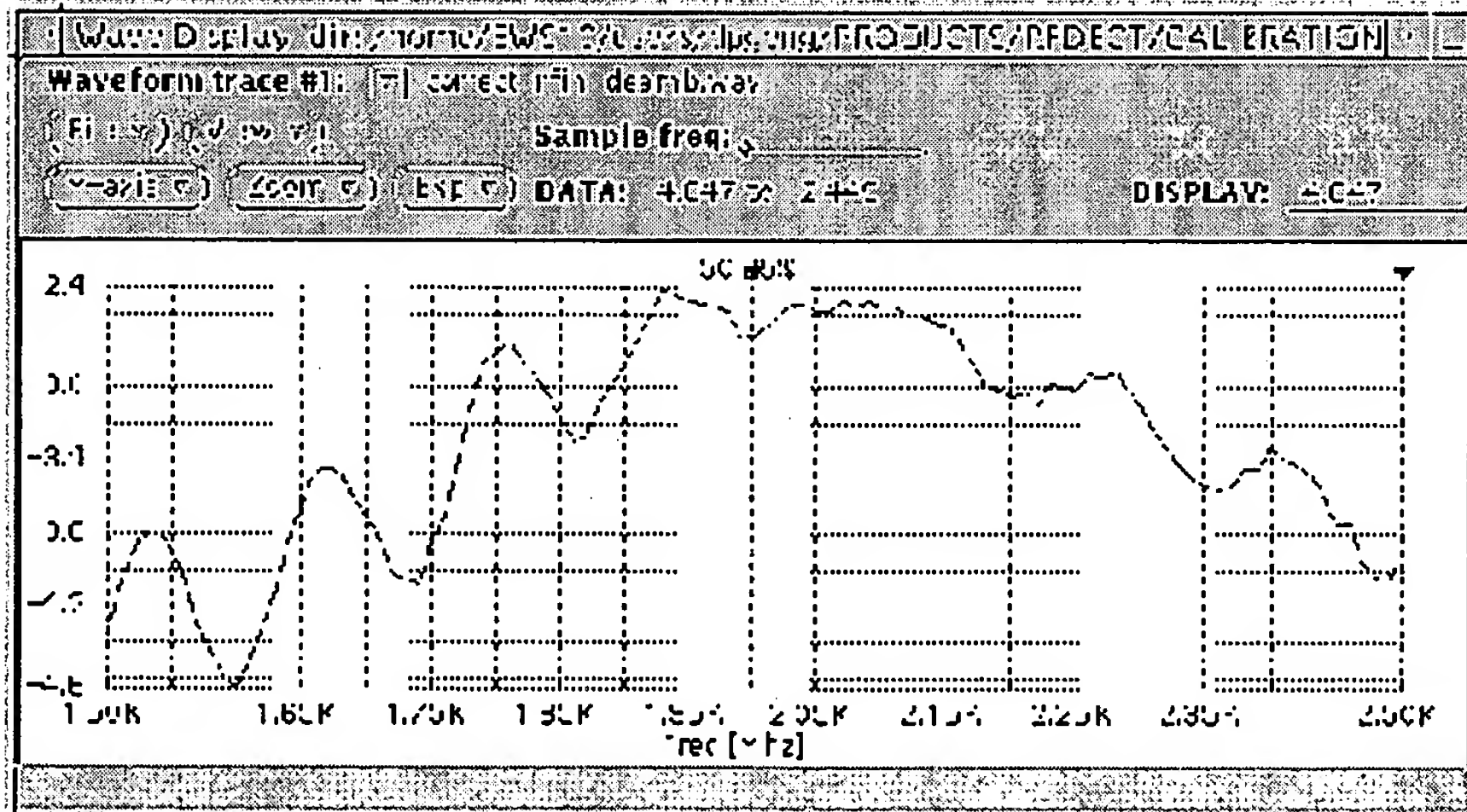


FIG. 29